

Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 1 of 54

CE RED EMC

For

Product: Wireless Microphone

Model: MO2665

Report No.: RKEYS250827253

Issued for

Mid Ocean Brands B.V.

Unit 711-716, 7/F., Tower A, 83 King Lam Street, Cheung Sha Wan, Kowloon, Hong Kong

Issued by

Guangdong KEYS Testing Technology Co., Ltd.

Address: Building 1, No.18, Shihuan Road, Dongcheng Subdistrict, Dongguan, Guangdong, China



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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 2 of 54

TABLE OF CONTENTS

1. TEST CERTIFICATION		<i></i>	. 3
2. TEST SUMMARY		<u> </u>	.4
3. TEST SITE			5
3.1. TEST FACILITY			. 5
3.2. MEASUREMENT UNCERTAINTY	1087		5
3.3. LIST OF TEST AND MEASUREMENT INSTRUMENTS	CE		. 5
3.3. LIST OF TEST AND MEASUREMENT INSTRUMENTS 4. EUT DESCRIPTION	A	Let !	10
5. TEST METHODOLOGY		(F)	11
5.1. TEST MODE			11
5.1. TEST MODE			11
6. SETUP OF EQUIPMENT UNDER TEST			12
6. SETUP OF EQUIPMENT UNDER TEST	120		12
6.2. CONFIGURATION OF SYSTEM UNDER TEST	CF.		12
7. EMISSION TEST			
7.1. CONDUCTED EMISSION MEASUREMENT			13
7.2. RADIATED EMISSION MEASUREMENT			17
7.3. RADIATED EMISSION MEASUREMENT(ABOVE 1GHz)			22
7.4. HARMONICS CURRENT MEASUREMENT			
7.5. VOLTAGE FLUCTUATION AND FLICKS MEASUREMENT			
8. IMMUNITY TEST	(F)		29
8.1. ELECTROSTATIC DISCHARGE (ESD)		1.6	32
8.2. RADIATED, RADIO-FREQUENCY, ELECTROMAGNETIC FIELI	O (RS)		36
8.3. ELECTRICAL FAST TRANSIENT (EFT)			39
8.4. SURGE IMMUNITY TEST			40
8.5. CONDUCTED RADIO FREQUENCY DISTURBANCES (CS) 8.6. VOLTAGE DIP & VOLTAGE INTERRUPTIONS		4	42
8.6. VOLTAGE DIP & VOLTAGE INTERRUPTIONS			44
9. PHOTOGRAPHS OF THE TEST CONFIGURATION	(&)	٠ ٢	46
10 PHOTOGRAPHS OF FUT	V	10	48

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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 3 of 54

1	. TEST CERT	FICATION
	Product:	Wireless Microphone
	Trade mark:	N/A
	Model:	MO2665
	Applicant:	Mid Ocean Brands B.V.
	Address:	Unit 711-716, 7/F., Tower A, 83 King Lam Street, Cheung Sha Wan, Kowloon, Hong Kong
	Manufacturer:	117486
	Address:	N/A
	Sample Received Date:	Aug. 27, 2025
	Test Date:	Aug. 27, 2025 to Aug. 29, 2025
6	Power supply:	Type-C Input: DC 5V, 1A Battery: DC 3.7V, 400mAh
	Applicable	ETSI EN 301 489-1 V2.2.3 (2019-11)
	Standards:	ETSI EN 301 489-17 V3.2.4 (2020-09)
	Remark:	
6	70	Co. Co.
	compliance with the this report only relative	nent has been tested by Guangdong KEYS Testing Technology Co., Ltd. and found the requirements in the technical standards mentioned above. The test results presented in the technical standards mentioned above. The test results presented in the technical standards mentioned above. The test results presented in the technical standards mentioned above. The test results presented in the technical standards mentioned above. The test results presented in the technical standards mentioned above. The test results presented in the technical standards mentioned above. The test results presented in the technical standards mentioned above. The test results presented in the technical standards mentioned above. The test results presented in the technical standards mentioned above. The test results presented in the technical standards mentioned above. The test results presented in the technical standards mentioned above. The test results presented in the technical standards mentioned above.
		Evan Fang
	Prepared by:	Evan Fang / Engineer
		b about

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Approved by:

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Bruce Zhang / Manager



Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 4 of 54

2. TEST SUMMARY

EMISSION									
Standard	Item	Result	Remarks						
EN 55032:2015/A1:2020	Conducted emission (Mains Port)	PASS	Complied with limit						
EN 33032.2013/A1.2020	Radiated emission	PASS	Complied with limit						
EN IEC 61000-3-2:2019+A1:2021	Harmonic current emissions	N/A	Not Applicable						
EN 61000-3-3:2013+A2:2021	Voltage fluctuations & flicker	N/A	Not Applicable						

IMMUNITY									
Standard	Item	Result	Remarks						
EN 61000-4-2:2009	ESD	PASS	Complied with the requirements						
EN IEC 61000-4-3:2006+A2: 2010	RS	PASS	Complied with the requirements						
EN 61000-4-4:2012	EFT	N/A	Not Applicable						
EN 61000-4-5:2014 +A1:2017	Surge	N/A	Not Applicable						
EN IEC 61000-4-6:2014	6 CS	N/A	Not Applicable						
EN IEC 61000-4-11:2004	Voltage dips & voltage variations	N/A	Not Applicable						

Note: 1) The test result verdict is decided by the limit of test standard

2)Not Applicable: The EUT is powered by DC.



Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 5 of 54

3. TEST SITE

3.1. TEST FACILITY

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3.2. MEASUREMENT UNCERTAINTY

Parameter	Uncertainty
Temperature	±1°C
Humidity	±5%
DC and Low Frequency Voltages	±3%
Conducted Emission(150KHz-30MHz)	±3.60dB
Radiated Emission(30MHz-1GHz)	±4.76dB
Radiated Emission (1GHz-18GHz)	±4.44dB

Note 1: This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.

3.3. LIST OF TEST AND MEASUREMENT INSTRUMENTS

3.3.1. For conducted emission at the mains terminals test

No.				110		
Name of Equipment	Manufacturer	Model	Equipment No.	Serial No.	Last Cal.	Cal. Interval
EMI Test Receiver	Rohde&Schwarz	ESCI	KEYS-EL-203	1166.5950.03-101 142	Mar. 03, 2025	1 Year
Pulse Limiter	Rohde&Schwarz	ESH3-Z2	KEYS-EL-201	0357.8810.54-101 857-hz	Mar. 03, 2025	1 Year
LISN	Rohde&Schwarz	ENV216	KEYS-EL-202	3560.6550.12-103 020-YU	Mar. 03, 2025	1 Year
Test software	Tonscend	JS32-CE Version 5.0.0				

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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 6 of 54

3.3.2. ⊠ For radiated emission test (30MHz-1GHz)

	Name of Equipment	Manufacturer	Model	Equipment No	Serial No.	Last Cal.	Cal. Interval	
į.	EMI Test Receiver	Rohde&Schwarz	ESCI7	KEYS-EL-205	1166.5950.03-10 0633	Mar. 03, 2025	1 Year	
	Logarithmic periodic antenna	Schwarzbeck	VULB9168	KEYS-EL-209	01145	Mar. 06, 2025	3 Year	
	Preamplifier	HP	8447F	KEYS-EL-210	1-18-53G22	Mar. 03, 2025	1 Year	
17	3m Anechoic Chamber	Taihe MaoRui	9*6*6	KEYS-EL-234	/	Oct. 09, 2024	5 Year	
	Test software	Tonscend	JS32-RE Version 5.0.0					

3.3.3. ⊠ For radiated emission test (1GHz above)

Name of	Manufacturer	Model	Equipment No.	Serial No.	Last Cal.	Cal. Interval	
Equipment							
EMI Test	Rohde&Schwarz	ESCI 7	KEYS-EL-205	1166.5950.03-	Mar. 03, 2025	1 Year	
Receiver	Ronde&Schwarz	ESCI /	ESCI / KEYS-EL-203	100633	Wiar. 03, 2023	1 Tear	
Horn	C -111-	DDII 4 0120D	LENG EL 220	02002	Mar. 06, 2025	2 3/2	
antenna	Schwarzbeck	Schwarzbeck BI	BBHA9120D KEYS-EL-239	03083	Mar. 06, 2025	3 Year	
Preamplifier	/	1-18-53G22	KEYS-EL-240	2501020026	Mar. 03, 2025	1 Year	
Test	T 1	IS22 DE V 5 0 0					
software	Tonscend		JS	32-RE Version 5.0	J.U		

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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 7 of 54

3.3.4. For harmonic current emissions and voltage fluctuations/flicker test

Name of Equipment	Manufacturer	Model	Equipment No.	Serial No.	Last Cal.	Cal. Interval
AC Power Source	California instruments	5001i-400	KEYS-EL-248	55979	May 17, 2025	1 Year
Harmonic and Flicker Analyzer	California instruments	PACS-1	KEYS-EL-249	72145	May 17, 2025	1 Year
Test software	California Instruments	CTS 4 Version 4.32.0				

3.3.5. \boxtimes For electrostatic discharge immunity test

Name of Equipment	Manufacturer	Model	Equipment No.	Serial No.	Last Cal.	Cal. Interval
ESD Tester	PRIMA	ESD6100 2TB	KEYS-EL-215	PR9240625 796	Mar. 05, 2025	1 Year

3.3.6. For radio frequency electromagnetic field immunity (R/S) test

Name of Equipment	Manufacturer	Model	Equipment No.	Serial No.	Last Cal.	Cal. Interval
Amplifier	Micotop	MPA-80-10 00-250	KEYS-EL-258	MAP25030 96	May 17, 2025	1 Year
Amplifier	Micotop	MPA-1000- 6000-100	KEYS-EL-259	MPA25030 98	May 19, 2025	1 Year
Power Meter	Agilent	E4417A	KEYS-EL-260	GB412933	May 17, 2025	1 Year
Power Sensor	Agilent	E9304A	KEYS-EL-261	MY552000	May 17, 2025	1 Year
Power Sensor	Agilent	E9304A	KEYS-EL-262	MY552000	May 17, 2025	1 Year
Signal Generator	ROHDE&SCH WARZ	SMB100A	KEYS-EL-263	102913	May 17, 2025	1 Year
Log-Per-Broad band Antenna	SKET	STLP 9129 PLUS	KEYS-EL-264	/	May 19, 2025	3 Year
Audio Analyzer	ROHDE&SCH WARZ	UPP200	KEYS-EL-267	120175	May 17, 2025	1 Year

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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 8 of 54

3.3.7. For electrical fast transient/burst immunity test

Name of Equipment	Manufacturer	Model	Equipment No.	Serial No.	Last Cal.	Cal. Interval
Fast Transient Burst Simulator	PRIMA	EFT61004TA	KEYS-EL-218	PR9240743972	Mar. 03, 2025	1 Year
Clamp	PRIMA	PEFT-C105	KEYS-EL-219	PEFT-1170	Mar. 03, 2025	1 Year

3.3.8. ☐ For surge immunity test

Name of Equipment	Manufacture r	Model	Equipment No.	Serial No.	Last Cal.	Cal. Interval
Lighting Surge Generator	PRIMA	SUG61005TB-22 16	KEYS-EL-217	PR200854619	Mar. 03, 2025	1 Year
Coupling/Decoupli	PRIMA	SUG-CDN-108	KEYS-EL-216	PR924105429	Mar. 03, 2025	1 Year

3.3.9. \square For injected currents susceptibility test

Name of Equipment	Manufacturer	Model	Equipment No. Serial No.		Last Cal.	Cal. Interval
CS Test system	TESEQ	NSG4070	KEYS-EL-255	30608	May 17, 2025	1 Year
6dB Attenuator	TESEQ	ATN6075	KEYS-EL-256	30783	May 17, 2025	1 Year
CDN	TESEQ	CDN M016	KEYS-EL-254	33518	May 17, 2025	1 Year
EM-Clamp	TESEQ	KEMZ 801A	KEYS-EL-257	33425	May 17, 2025	1 Year

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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 9 of 54

3.3.10. For power frequency magnetic field immunity test

Name of Equipment	Manufacturer	Model	Equipment NO.	Serial No.	Last Cal.	Cal. Interval
POWER	0.5			(10)	0.0	6
FREQUENCY	(Te	EMS61000-8			May 16,	
MAGNETIC	EVERFINE	K	KEYS-EL-273	608002	2025	1 Year
FIELD		K	650		2023	6
GENERATION			9	05		

3.3.11. \square For voltage dips and short interruptions immunity test

Name of Equipment	Manufacturer	Model	Equipment No.	Serial No.	Last Cal.	Cal. Interval
Cycle Sag Simulator	PRIMA	DRP61011TB	KEYS-EL-220	PR924086817	Mar. 03, 2025	1 Year

Note:

The test equipment corresponds to the test items. (The selected checkbox indicates that the equipment has been used during testing, while the unselected one indicates that the equipment has not been used.)

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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 10 of 54

4. EUT DESCRIPTION

Product	Wireless Microphone	Cers		
Model	MO2665	9	Caro	
RF Specification	Bluetooth		9	d
Supplied Voltage	Type-C Input: DC 5V, 1A Battery: DC 3.7V, 400mAh	055		Q

I/O PORT

I/O PORT TYPES	Q'TY	TESTED WITH		
AC Port	1 65			
DC Port	1 🕏			

Models Difference

N/A

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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 11 of 54

5. TEST METHODOLOGY

5.1. TEST MODE

The EUT was tested together with the thereinafter additional components, and a configuration, which produced the worst emission levels, was selected and recorded in this report.

Test Mode 1	EUT + Bluetooth Link	15		7
Test Mode 2	EUT +TF Card	(TO)	2 (2	

The following test mode(s) were assessed.

	Test Items	Test Mode
	Conducted Emission	Mode 1
	Radiated Emission	Mode 1
Emission	Radiated Emission above 1HGz	Mode 1
	Harmonic current emissions	N/A
	Voltage fluctuations & flicker	N/A
	ESD	Mode 1
	RS	Mode 1
Immorraites	EFT	N/A
Immunity	Surge	N/A
	C/S	N/A
	Dips	N/A

Note:Only the worse mode was record in this report.

5.2. EUT SYSTEM OPERATION

- 1. Set up EUT with the support equipment.
- 2. Make sure the EUT work normally during the test.

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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 12 of 54

6. SETUP OF EQUIPMENT UNDER TEST

6.1. DESCRIPTION OF SUPPORT UNITS

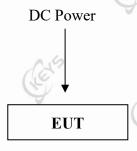
The EUT has been tested as an independent unit together with other necessary accessories or support units. The following support units or accessories were used to form a representative test configuration during the tests.

No.	Equipment	Model	Manufacturer.		
1.	Adapter	1	Xiaomi		

Note: 1) All the equipment/cables were placed in the worst-case configuration to maximize the emission during the test.

2) Grounding was established in accordance with the manufacturer's requirements and conditions for the intended use.

6.2. CONFIGURATION OF SYSTEM UNDER TEST



(EUT: Wireless Microphone)

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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 13 of 54

7. EMISSION TEST

7.1. CONDUCTED EMISSION MEASUREMENT

7.1.1. LIMIT

EDEOLIENCY	Cla	ss A	Class B		
FREQUENCY (MHz)	Quasi-peak Average dB(μV) dB(μV)		Quasi-peak dB(μV)	Average dB(μV)	
0.15 - 0.5	79	66	66-56	56-46	
0.5 - 5.0	73	60	56	46	
5.0 - 30.0	73	60	60	50	

Note: 1) The lower limit shall apply at the transition frequencies.

2) The limit decreases in line with the logarithm of the frequency in the range of 0.15 MHz to 0.5 MHz

7.1.2. TEST PROCEDURE

The EUT and Support equipment, if needed, was set up as per the test configuration to simulate typical usage per the user's manual. When the EUT is a tabletop system, a wooden table with a height of 0.8 meters is used and is placed on the ground plane. When the EUT is floor standing equipment, it is placed on the ground plane, which has a 3-12 mm non-conductive covering to insulate the EUT from the ground plane. The EUT should be 0.8 m apart from the AMN, where the mains cable supplied by the manufacturer is longer than 0.8 m, the excess should be folded at the centre into a bundle no longer than 0.4 m, Details please refer to test setup photography.

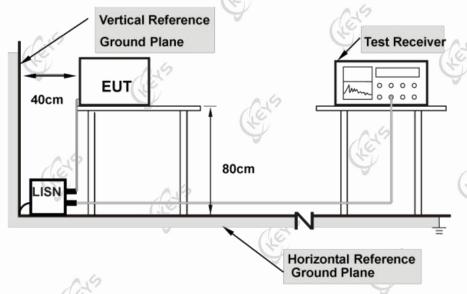
The Receiver scanned from 9 kHz to 30 MHz for emissions in each of the test modes. During the above scans, the emissions were maximized by cable manipulation.

A scanning was taken on the power lines, Line and neutral, recording at least six highest emissions. Emission frequency and amplitude were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit. The test data of the worst-case condition(s) was recorded.



Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 14 of 54

7.1.3. TEST SETUP



Note: 1.Support units were connected to second LISN.

2.Both of LISNs(AMN) are 80 cm from EUT and at least 80 from other units and other metal planes

7.1.4. TEST RESULT

/ \ \ \ /			4.10
Product name	Wireless Microphone	Tested By	Joy Jiang
Model	MO2665	Detector Function	Quasi-peak/AV
Test Mode	Mode 1	6 dB Bandwidth	9 kHz
Environmental Conditions	24.3°C,53% RH, 101.1 kPa	Test Result	Pass

Note:

L = Line Line, N = Neutral Line

Freq. = Emission frequency in MHz

Reading level $(dB\mu V)$ = Receiver reading

Corr. Factor (dB) = attenuator + Cable loss

Level $(dB\mu V)$ = Reading level $(dB\mu V)$ + Corr. Factor (dB)

Limit $(dB\mu V)$ = Limit stated in standard

Over Limit (dB) = Level (dB μ V) – Limit (dB μ V)

QP = Quasi-Peak

AV = Average

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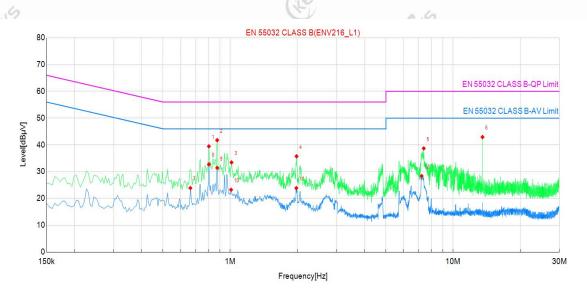
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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 15 of 54

Please refer to the following diagram:

Line:



_				A 100					
Suspe	cted Data Lis	t							
NO.	Frequency [MHz]	Reading [dBµV]	Level [dBµV]	Factor [dB]	Limit [dBµV]	Margin [dB]	Phase	Detector	Verdict
1	0.802500	20.20	39.46	19.26	56.00	16.54	L1	QP	PASS
2	0.874500	22.52	41.76	19.24	56.00	14.24	L1	QP	PASS
3	1.014000	14.26	33.46	19.20	56.00	22.54	L1	QP	PASS
4	1.986000	16.54	35.74	19.20	56.00	20.26	L1	QP	PASS
5	7.390500	19.52	38.70	19.18	60.00	21.30	L1	QP	PASS
6	13.560000	23.62	42.93	19.31	60.00	17.07	L1	QP	PASS
7	0.663000	4.64	23.89	19.25	46.00	22.11	L1	AV	PASS
8	0.802500	13.48	32.74	19.26	46.00	13.26	L1	AV	PASS
9	0.874500	12.18	31.42	19.24	46.00	14.58	L1	AV	PASS
10	1.009500	4.05	23.25	19.20	46.00	22.75	L1	AV	PASS
11	1.981500	4.68	23.88	19.20	46.00	22.12	L1	AV	PASS
12	7.233000	9.21	28.37	19.16	50.00	21.63	L1	AV	PASS

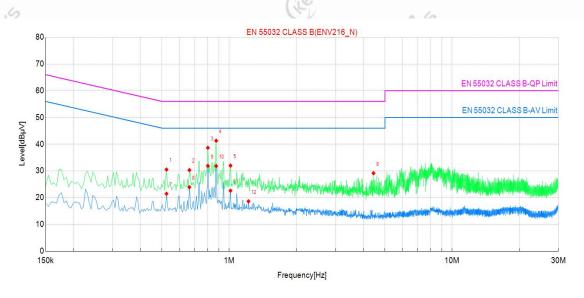
Note:(1)Level=Reading+Factor (2)Margin=Limit-Level

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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 16 of 54

Neutral:



Suspe	ected Data Lis	t							
NO.	Frequency [MHz]	Reading [dBµV]	Level [dBµV]	Factor [dB]	Limit [dBµV]	Margin [dB]	Phase	Detector	Verdict
1	0.523500	11.30	30.50	19.20	56.00	25.50	N	QP	PASS
2	0.663000	11.04	30.31	19.27	56.00	25.69	N	QP	PASS
3	0.802500	19.39	38.65	19.26	56.00	17.35	N	QP	PASS
4	0.874500	22.06	41.30	19.24	56.00	14.70	N	QP	PASS
5	1.014000	12.78	31.98	19.20	56.00	24.02	N	QP	PASS
6	4.443000	10.00	29.16	19.16	56.00	26.84	N	QP	PASS
7	0.523500	2.27	21.47	19.20	46.00	24.53	N	AV	PASS
8	0.663000	4.67	23.94	19.27	46.00	22.06	N	AV	PASS
9	0.802500	12.62	31.88	19.26	46.00	14.12	N	AV	PASS
10	0.874500	12.58	31.82	19.24	46.00	14.18	N	AV	PASS
11	1.014000	3.41	22.61	19.20	46.00	23.39	N	AV	PASS
12	1.221000	-0.57	18.63	19.20	46.00	27.37	N	AV	PASS

Note:(1)Level=Reading+Factor (2)Margin=Limit-Level

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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 17 of 54

7.2. RADIATED EMISSION MEASUREMENT

7.2.1. LIMITS

1	FREQUENCY (MHz)	Distance m	Quasi Peak dB(μV/m)		
ľ	30~230	3 0.5	40		
ĺ	230~1000	3	47		

Note: 1) The lower limit shall apply at the transition frequencies.

2) Emission level ($dB\mu V/m$) = 20 log Emission level ($\mu V/m$).

7.2.2. TEST PROCEDURE

- a. The EUT was placed on the top of an insulating table 0.8 meters above the ground at a semi-anechoic chamber. The table was rotated 360 degrees to determine the position of the highest radiation.
- b. The EUT was set 3 meters away from the interference-receiving antenna, which was mounted on the top of a variable-height antenna tower.
- c. The antenna is a broadband antenna, and its height is varied from 1 to 4 meter above the ground to determine the maximum value of the field strength. Both horizontal and vertical polarization of the antenna are set to make the measurement.
- d. For each suspected emission, the EUT was arranged to its worst case and then the antenna was tuned to the heights from 1 to 4 meters and the ratable table was turned from 0 degrees to 360 degrees to find the maximum reading.
- e. The test-receiver system was set to Peak Detector Function and Specified Bandwidth with Maximum Hold Mode when the test frequency is below 1GHz.

Note:

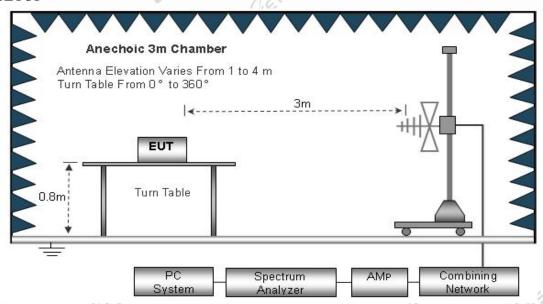
- 1.The resolution bandwidth of test receiver/spectrum analyzer is 120khz for quasi-peak detection(QP) at frequency below 1GHz.
- 2.Emission level(dBμV/m)=Raw Value(dBμV)+Correction Factor(dB/m)
- 3.Correction Factor(dB/m)=Antenna Factor(dB/m)+ Correction Factor(dB)(if the raw value not contains the amplifier);
- 4. Correction Factor(dB/m)=Antenna Factor(dB/m)+ Correction Factor(dB)-Amplifer Gain(dB)(if the raw value contains the amplifier).
 - 5.Margin value=Emission level-Limit value.

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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 18 of 54

7.2.3. TEST SETUP



Note: For the actual test configuration, please refer to the related item – Photographs of the Test Configuration

Test distance define

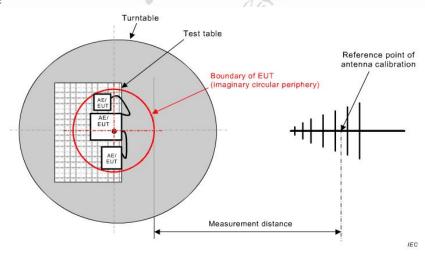


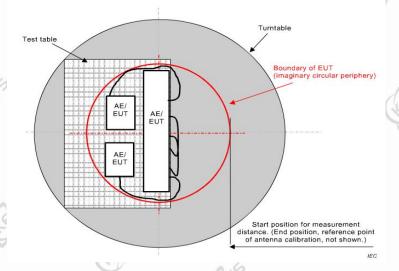
Figure C.1 - Measurement distance

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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 19 of 54



7.2.4. TEST RESULT

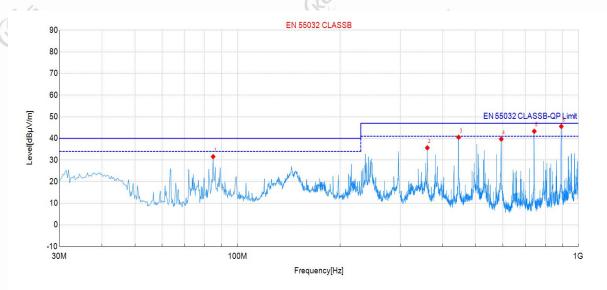
Product name	Wireless Microphone	Tested By	Joy Jiang			
Model	MO2665	Detector Function	Quasi-peak			
Test Mode	Mode 1	RBW	120kHz			
Environmental Conditions	24.3°C, 52% RH, 101.1 kPa	Test Result	Pass			



Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 20 of 54

Please refer to the following diagram:

Vertical:



Susp	Suspected Data List										
NO.	Frequency [MHz]	Reading [dBµV]	Level [dBµV/m]	Factor [dB/m]	Limit [dBµV/m]	Margin [dB]	Height [cm]	Angle [°]	Det	Pol	Verdict
1	84.81	52.16	31.56	-20.60	40.00	8.44	100	353	QP	Vert	PASS
2	360.53	51.02	35.65	-15.37	47.00	11.35	100	34	QP	Vert	PASS
3	445.40	53.98	40.51	-13.47	47.00	6.49	100	324	QP	Vert	PASS
4	594.06	49.91	39.68	-10.23	47.00	7.32	100	52	QP	Vert	PASS
5	742.47	51.73	43.30	-8.43	47.00	3.70	100	287	QP	Vert	PASS
6	891.12	52.81	45.55	-7.26	47.00	1.45	100	2	QP	Vert	PASS

(+)

Note:(1)Level=Reading+Factor (2)Margin=Limit-Level



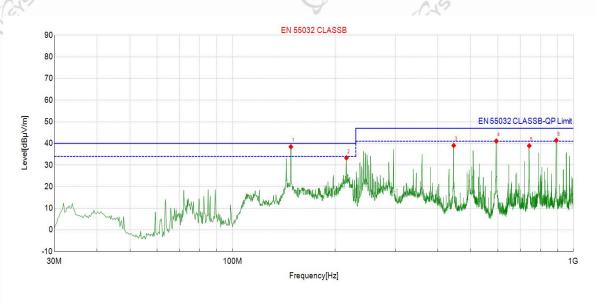
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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 21 of 54

Please refer to the following diagram:

Horizontal::



Susp	Suspected Data List										
NO.	Frequency [MHz]	Reading [dBµV]	Level [dBµV/m]	Factor [dB/m]	Limit [dBµV/m]	Margin [dB]	Height [cm]	Angle [°]	Det	Pol	Verdict
1	148.34	54.63	38.44	-16.19	40.00	1.56	100	344	QP	Hori	PASS
2	216.00	52.62	33.29	-19.33	40.00	6.71	100	316	QP	Hori	PASS
3	445.65	52.50	39.03	-13.47	47.00	7.97	100	316	QP	Hori	PASS
4	594.06	51.31	41.08	-10.23	47.00	5.92	100	0	QP	Hori	PASS
5	742.47	47.33	38.90	-8.43	47.00	8.10	100	174	QP	Hori	PASS
6	891.12	48.65	41.39	-7.26	47.00	5.61	100	288	QP	Hori	PASS
					(+)						

Note:(1)Level=Reading+Factor (2)Margin=Limit-Level

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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 22 of 54

7.3. RADIATED EMISSION MEASUREMENT (ABOVE 1GHz)

7.3.1. LIMITS

FREQUENCY (MHz)	Distance m	Peak dB(μV/m)	Average dB(μV/m)		
1000~3000	3	50	54		
3000~ 6000	3	70	74		

Note: 1) The lower limit shall apply at the transition frequencies.

2) Emission level (dB μ V/m) = 20 log Emission level (μ V/m).

7.3.2. TEST PROCEDURE

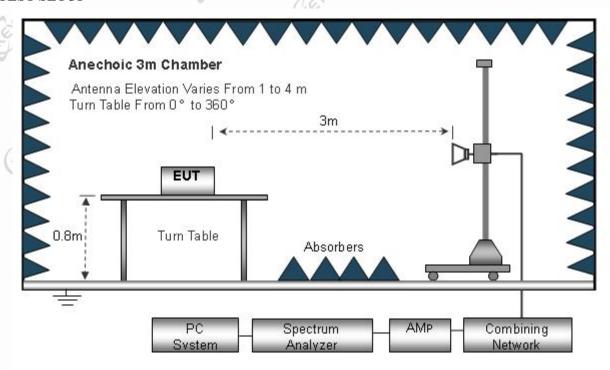
- a. The EUT was placed on the top of an insulating table 0.8 meters above the ground at a semi-anechoic chamber. The table was rotated 360 degrees to determine the position of the highest radiation.
- b. The EUT was set 3 meters away from the interference-receiving antenna, which was mounted on the top of a variable-height antenna tower.
- c. The height of antenna is varied from 1 to 4 meter above the ground ,the height of adjustment depends on the EUT height and the antenna 3dB bandwidth both,to determine the maximum value of the field strength. Both horizontal and vertical polarization of the antenna are set to make the measurement. The boresight should be used during the test above 1GHz.
- d. For each suspected emission, the EUT was arranged to its worst case and then the antenna was tuned to the heights from 1 to 4 meters and the ratable table was turned from 0 degrees to 360 degrees to find the maximum reading.
- e. The test-receiver system was set to Peak Detector Function and Specified Bandwidth with Maximum Hold Mode when the test frequency is above 1 GHz.





Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 23 of 54

7.3.3. TEST SETUP



Note: For the actual test configuration, please refer to the related item - Photographs of the Test Configuration

7.3.4. TEST RESULT

Product name	Wireless Microphone	Tested By	Joy Jiang
Model	MO2665	Detector Function	Peak/AV
Test Mode	Mode 1	RBW	1MHz
Environmental Conditions	24.3°C, 52% RH, 101.1 kPa	Test Result	Pass

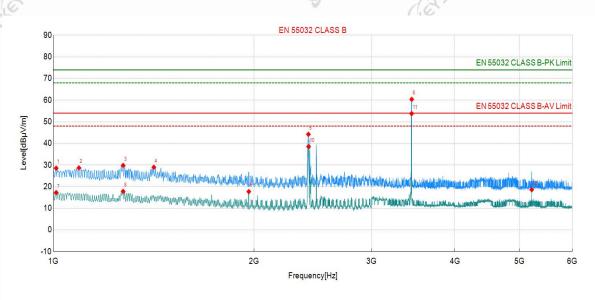
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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 24 of 54

Please refer to the following diagram:

Vertical:



Susp	ected Data L	ist									
NO.	Frequency [MHz]	Reading [dBµV]	Level [dBµV/m]	Factor [dB/m]	Limit [dBµV/m]	Margin [dB]	Height [cm]	Angle [°]	Det	Pol	Verdict
1	1010.00	60.74	28.54	-32.20	74.00	45.46	100	360	PK	Vert	PASS
2	1092.50	61.29	28.67	-32.62	74.00	45.33	100	326	PK	Vert	PASS
3	1272.50	63.35	29.81	-33.54	74.00	44.19	100	295	PK	Vert	PASS
4	1415.00	63.24	28.97	-34.27	74.00	45.03	100	295	PK	Vert	PASS
5	2412.50	80.72	44.21	-36.51	74.00	29.79	100	161	PK	Vert	PASS
6	3446.25	95.63	60.38	-35.25	74.00	13.62	100	1	PK	Vert	PASS
7	1010.00	49.45	17.25	-32.20	54.00	36.75	100	17	AV	Vert	PASS
8	1272.50	51.35	17.81	-33.54	54.00	36.19	100	28	AV	Vert	PASS
9	1963.75	54.78	17.72	-37.06	54.00	36.28	100	28	AV	Vert	PASS
10	2413.75	75.03	38.52	-36.51	54.00	15.48	100	326	AV	Vert	PASS
11	3445.00	89.04	53.79	-35.25	54.00	0.21	100	1	AV	Vert	PASS
12	5215.00	52.97	18.60	-34.37	54.00	35.40	100	285	AV	Vert	PASS

Note:(1)Level=Reading+Factor (2)Margin=Limit-Level

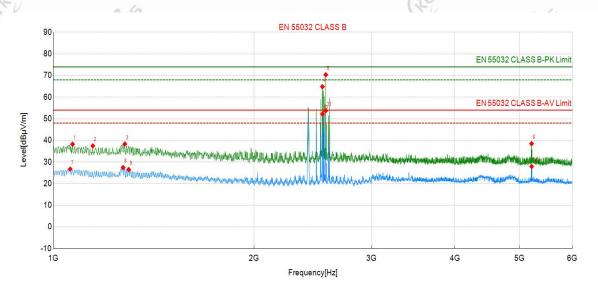
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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 25 of 54

Please refer to the following diagram:

Horizontal::



Susp	ected Data L	ist		V.	07	V1		e.	50)		٨
NO.	Frequency [MHz]	Reading [dBµV]	Level [dBµV/m]	Factor [dB/m]	Limit [dBµV/m]	Margin [dB]	Height [cm]	Angle [°]	Det	Pol	Verdict
1	1068.75	70.74	38.24	-32.50	74.00	35.76	100	146	PK	Hori	PASS
2	1146.25	70.34	37.45	-32.89	74.00	36.55	100	135	PK	Hori	PASS
3	1280.00	71.90	38.32	-33.58	74.00	35.68	100	84	PK	Hori	PASS
4	2532.50	101.15	64.84	-36.31	74.00	9.16	100	43	PK	Hori	PASS
5	2561.25	106.60	70.35	-36.25	74.00	3.65	100	187	PK	Hori	PASS
6	5212.50	72.87	38.49	-34.38	74.00	35.51	100	240	PK	Hori	PASS
7	1060.00	59.19	26.74	-32.45	54.00	27.26	100	0	AV	Hori	PASS
8	1272.50	60.99	27.45	-33.54	54.00	26.55	100	74	AV	Hori	PASS
9	1297.50	60.19	26.52	-33.67	54.00	27.48	100	292	AV	Hori	PASS
10	2532.50	88.51	52.20	-36.31	54.00	1.80	100	43	AV	Hori	PASS
11	2561.25	89.95	53.70	-36.25	54.00	0.30	100	199	AV	Hori	PASS
12	5213.75	62.29	27.92	-34.37	54.00	26.08	100	251	AV	Hori	PASS

Note:(1)Level=Reading+Factor (2)Margin=Limit-Level

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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 26 of 54

7.4. HARMONICS CURRENT MEASUREMENT

7.4.1. LIMITS OF HARMONICS CURRENT MEASUREMENT

	n (n							
Limit fo	r Class A equipment							
Harmoni	Max. permissible							
cs Order	harmonics current							
N	A							
Odd harmonics								
3	2.30							
5	1.14							
7	0.77							
9	0.40							
11	0.33							
13	0.21							
15≦n≦	0.15(15/-)							
39	0.15x(15/n)							
E	ven harmonics							
2	1.08							
4	0.43							
6	0.30							
8≦n≦4	0.22-0/							
0	0.23x8/n							

		A.6
	Limit for Class D equ	ipment
Harmonics Order	Max. permissible	Max. permissible harmonics
n	harmonics current per	current
11	watt mA/W	A
	Odd Harmonics of	nly
3	3.4	2.30
5,6	1.9	1.14
(7	1.0	0.77
9	0.5	0.40
11	0.35	0.33
13	0.30	0.21
15≦n≦39	,	(LE
(odd harmonics	3.85/n	0.15x(15/n)
only)	16	
	(Te)	2 /2
	7	
		A 150
(E)		

			110		
(E)	Li	mit for Class C equip	oment	125	
Harmonics Order	Max	x. permissible harmon	ics current	expressed as a pe	ercentage of the
n	(Fe)	input current	at the fundar	mental frequency	A (C)
2	A	(E)	2		9
3		9	30xF	7	
5,6			10	0.60	
(4.)	. (0		7	(6)	
9	(6		5	9	(2)
11≦n<≦39	4	05			
(odd harmonics only)		(te	3		
F is the circuit power factor		4	(E)		

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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 27 of 54

Note: Class A, B, C and D are classified according to item 7.4.2.of this report

7.4.2. TEST PROCEDURE

The EUT was placed on the top of a wooden table 0.8 meters above the ground and operated to produce the maximum harmonic. The classification of EUT is according to section 5 of EN 61000-3-2.

The EUT is classified as follows:

Class A:

Balanced three-phase equipment, Household appliances excluding equipment as Class D, Tools excluding portable tools, Dimmers for incandescent lamps, audio equipment, equipment not specified in one of the three other classes.

Class B:

Portable tools; Arc welding equipment which is not professional equipment.

Class C:

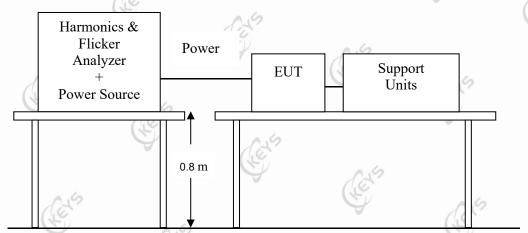
Lighting equipment

Class D:

Equipment having a specified power less than or equal to 600 W of the following types: Personal computers and personal computer monitors and television receivers.

The correspondent test program of test instrument to measure the current harmonics emanated from EUT is chosen. The measure time shall be not less than the time necessary for the EUT to be exercised.

7.4.3. TEST SETUP



For the actual test configuration, please refer to the related item – Photographs of the Test Configuration.

7.4.4. TEST RESULT

N/A

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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 28 of 54

7.5. VOLTAGE FLUCTUATION AND FLICKS MEASUREMENT

7.5.1. LIMITS OF VOLTAGE FLUCTUATION AND FLICKS MEASUREMENT

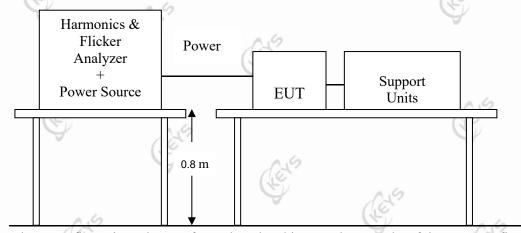
TEST ITEM	LIMIT	REMARK	
P_{st}	1.0	P _{st} means short-term flicker indicator.	
P _{lt}	0.65	P _{lt} means long-term flicker indicator.	
T _{dt} (ms)	500	T _{dt} means maximum time that dt exceeds 3 %.	
d _{max} (%)	4/6/7 %	d _{max} means maximum relative voltage change.	
dc (%)	3.3 %	dc means relative steady-state voltage change	

7.5.2. TEST PROCEDURE

The EUT was placed on the top of a wooden table 0.8 meters above the ground and operated to produce the most unfavorable sequence of voltage changes under lighting operating conditions.

During the flick measurement, the measure time shall include that part of whole operation cycle in which the EUT produce the most unfavorable sequence of voltage changes. The observation period for short-term flicker indicator is 10 minutes and the observation period for long-term flicker indicator is 2 hours.

7.5.3. TEST SETUP



For the actual test configuration, please refer to the related item – Photographs of the Test Configuration.

7.5.4. TEST RESULT

N/A

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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 29 of 54

8. IMMUNITY TEST

PERFORMANCE CRITERIA DESCRIPTION

EN 301 489-1 V2.2.3 Clause 6 requirements:

Performance criteria for continuous phenomena

During the test, the equipment shall:

- continue to operate as intended;
- not unintentionally transmit;
- not unintentionally change its operating state;
- not unintentionally change critical stored data

Performance criteria for transient phenomena

For all ports and transient phenomena with the exception described below, the following applies:

- The application of the transient phenomena shall not result in a change of the mode of operation (e.g. unintended transmission) or the loss of critical stored data.
- After application of the transient phenomena, the equipment shall operate as intended.

For surges applied to symmetrically operated wired network ports intended to be connected directly to outdoor lines the following criteria applies:

- For products with only one symmetrical port intended for connection to outdoor lines, loss of function is allowed, provided the function is self-recoverable, or can be otherwise restored. Information stored in non-volatile memory, or protected by a battery backup, shall not be lost.
- For products with more than one symmetrical port intended for connection to outdoor lines, loss of function on the port under test is allowed, provided the function is self-recoverable. Information stored in non-volatile memory, or protected by a battery backup, shall not be lost.

EN 301 489-17 V3.2.4 Clause 6 requirements:

- 6 General performance criteria
- 6.1The performance criteria are:
- performance criteria A for immunity tests with phenomena of a continuous nature;
- performance criteria B for immunity tests with phenomena of a transient nature;
- performance criteria C for immunity tests with power interruptions exceeding a certain time.

The equipment shall meet the minimum performance criteria as specified in the following clauses.

- 6.2 Performance table
- 6.2.1 Performance criteria overview

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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 30 of 54

Criteria	During test	After test	
1.62		(i.e. as a result of the application of the test)	
A	Shall operate as intended.	Shall operate as intended.	
	(See note).	Shall be no degradation of performance.	
	Shall be no loss of function.	Shall be no loss of function.	
	Shall be no unintentional transmissions.	Shall be no loss of critical stored data.	
BAS	May be loss of function.	Functions shall be self-recoverable.	
(4)	0.50	Shall operate as intended after recovering.	
	(6)	Shall be no loss of critical stored data.	
С	May be loss of function.	Functions shall be recoverable by the operator.	
	9	Shall operate as intended after recovering.	
16	6	Shall be no loss of critical stored data	
NOTE: Operat	e as intended during the test allows a level of	of degradation in accordance with clause 6.2.2.	

6.2.2 Minimum performance level

For equipment that supports a PER or FER, the minimum performance level shall be a PER or FER less than or equal to 10 %.

For equipment that does not support a PER or a FER, the minimum performance level shall be no loss of the wireless transmission function needed for the intended use of the equipment.

6.3 Performance criteria for Continuous phenomena

The performance criteria A shall apply.

Where the EUT is a transmitter in standby mode, unintentional transmission shall not occur during the test.

Where the EUT is a transceiver in receive mode, unintentional transmission shall not occur during the test.

6.4 Performance criteria for Transient phenomena

The performance criteria B shall apply, except for voltage dips greater than or equal to 100 ms and voltage interruptions of 5 000 ms duration, for which performance criteria C shall apply.

Where the EUT is a transmitter in standby mode, unintentional transmission shall not occur as a result of the application of the test.

Where the EUT is a transceiver in receive mode, unintentional transmission shall not occur as a result of the application of the test.

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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 31 of 54

	4.9
Criteria A:	During and after the test the EUT shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed below a minimum performance level specified by the manufacturer when the EUT is used as intended. The performance level may be replaced by a permissible loss of performance. If the minimum performance level or the permissible performance loss is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the EUT if used as intended.
Criteria B:	After the test, the EUT shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed, after the application of the phenomena below a performance level specified by the manufacturer, when the EUT is used as intended. The performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is allowed. However, no change of operating state or stored data is allowed to persist after the test. If the minimum performance level (or the permissible performance loss) is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the EUT if used as intended.
Criteria C:	During and after testing, a temporary loss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls or cycling of the power to the EUT by the user in accordance with the manufacturer's instructions. Functions, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be lost.



Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 32 of 54

8.1. ELECTROSTATIC DISCHARGE (ESD)

8.1.1. TEST SPECIFICATION

Test Standard: EN 301 489-1/-17

Basic Standard: EN 61000-4-2

Discharge Impedance: 330Ω

Charging Capacity: 150 pF

Discharge Voltage: Air Discharge: ±8 kV (Direct)

Contact Discharge: ± 4 kV (Direct/Indirect)

Polarity: Positive & Negative

Number of Discharge: 10 (Air discharge for single polarity discharge)

10 (Contact discharge for single polarity discharge)

Discharge Mode: 1 time/s

Performance Criterion: B

8.1.2. TEST PROCEDURE

The discharges shall be applied in two ways:

- a) Contact discharges to the conductive surfaces and coupling planes:
 - 20 dischargers (10 with positive and10 with negative polarity) shall be applied on each accessible metallic part of the enclosure, terminals are excluded. In case of a non-conductive enclosure, dischargers shall be applied on the horizontal or vertical coupling planes. Test shall be performed at a maximum repetition rate of one discharge per second.
- b) Air discharges at slots and apertures and insulating surfaces:

On those parts of the EUT where it is not possible to perform contact discharge testing, the equipment should be investigated to identify user accessible points where breakdown may occur. Such points are tested using the air discharge method. This investigation should be restricted to those area normally handled by the user. A minimum of 10 single air discharges shall be applied to the selected test point for each such area.

The basic test procedure was in accordance with EN 61000-4-2:

- a) The EUT was located 0.1 m minimum from all side of the HCP (dimensions 1.6 m x 0.8 m).
- b) The support units were located another table 30 cm away from the EUT, but direct support unit was/were located at same location as EUT on the HCP and keep at a distance of 10cm with EUT.
- c) The time interval between two successive single discharges was at least 1 second.
- d) Contact discharges were applied to the non-insulating coating, with the pointed tip of the generator penetrating the coating and contacting the conducting substrate.

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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 33 of 54

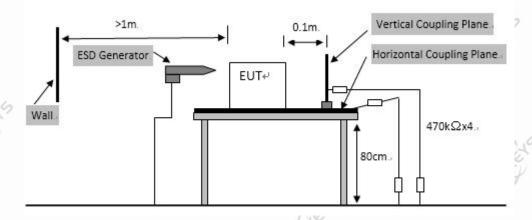
- e) Air discharges were applied with the round discharge tip of the discharge electrode approaching the EUT as fast as possible (without causing mechanical damage) to touch the EUT. After each discharge, the ESD generator was removed from the EUT and re-triggered for a new single discharge. The test was repeated until all discharges were complete.
- f) At least ten single discharges (in the most sensitive polarity) were applied at the front edge of each HCP opposite the center point of each unit of the EUT and 0.1 meter from the front of the EUT. The long axis of the discharge electrode was in the plane of the HCP and perpendicular to its front edge during the discharge.
- g) At least ten single discharges (in the most sensitive polarity) were applied to the center of one vertical edge of the Vertical Coupling Plane (VCP) in sufficiently different positions that the four faces of the EUT were completely illuminated. The VCP (dimensions 0.5 m x 0.5 m) was placed vertically to and 0.1 meter from the EUT

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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 34 of 54

8.1.3. TEST SETUP



For the actual test configuration, please refer to the related item – Photographs of the Test Configuration.

Note:

1) TABLE-TOP EQUIPMENT

The GRP consisted of a wooden table 0.8 meters high standing on the ground reference plane (GRP). The GRP consisted of a sheet of aluminum at least 0.25 mm thick, and 2.5 meters square connected to the protective grounding system. A horizontal coupling plane (HCP) $(1.6 \text{ m} \times 0.8 \text{ m})$ was placed on the table and attached to the GRP by means of a cable with 940k total impedance. The equipment under test, was installed in a representative system as described in section 7 of EN 61000-4-2, and its cables were placed on the HCP and isolated by an insulating support of 0.5 mm thickness. A distance of 1-meter minimum was provided between the EUT and the walls of the laboratory and any other metallic structure.

2) FLOOR-STANDING EQUIPMENT

The equipment under test was installed in a representative system as described in section 7 of IEC 61000-4-2, and its cables were isolated from the ground reference plane by an insulating support of 0.1 meter thickness. The GRP consisted of a sheet of aluminum that is at least 0.25 mm thick, and 2.5 meters square connected to the protective grounding system and extended at least 0.5 meters from the EUT on all sides.

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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 35 of 54

8.1.4. TEST RESULT

Product	Wireless Microphone	Environmental Conditions	24.1°C, 55% RH, 101.14 kPa		
Model	MO2665	Tested By	Joy Jiang		
Test mode	Mode 1	Test Result	Pass		

Discharge Type	Level (kV)	Test Point	Observation	Performance Criterion
Contact Discharge	±4	1	Note \square 1 \boxtimes 2 \square 3	A A
Direct Air Discharge	± 8	2 65	Note \square 1 \boxtimes 2 \square 3	A
Indirect Discharge (HCP)	± 4	3	Note $\square 1 \boxtimes 2 \square 3$	В
Indirect Discharge (VCP)	±4	3	Note □ 1 ⊠ 2 □ 3	B

Test point:

- 1. All insulated enclosure and seams.
- 2.All accessible metal parts of the enclosure
- 3.All side

Note:

- 1) No degradation in performance of the EUT was observed.
- 2) During the test, Loss of functionality, after the experiment, the function can automatically return to normal.
- 3) Loss of functionality, but self-recoverable by user, without loss of information or settings.

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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 36 of 54

8.2. RADIATED, RADIO-FREQUENCY, ELECTROMAGNETIC FIELD (RS)

8.2.1. TEST SPECIFICATION

Test Standard: EN 301 489-1/-17
Basic Standard: EN IEC 61000-4-3

Frequency Range: 80 ~6GHz 80 MHz ~ 1000 MHz, 1800MHz,

2600MHz, 3500MHz, 5000MHz

Field Strength: 3 V/m

Modulation: 1 kHz Sine Wave, 80 %, AM Modulation

Frequency Step: 1 % of preceding frequency value

Polarity of Antenna: Horizontal and Vertical

Test Distance: 3 m
Antenna Height: 1.5 m
Performance Criterion: A

8.2.2. TEST PROCEDURE

The test procedure was in accordance with EN IEC 61000-4-3

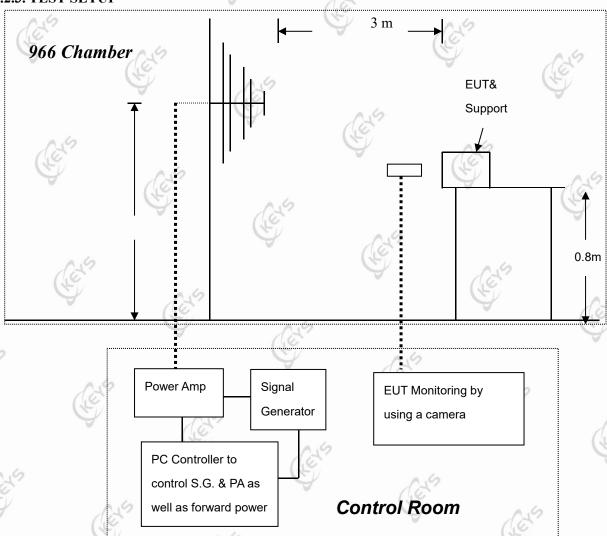
- a) The testing was performed in a fully anechoic chamber. The transmit antenna was located at a distance of 3 meters from the EUT.
- b) The frequency range is swept from 80 MHz to 1000 MHz, with the signal 80% amplitude modulated with a 1 kHz sine-wave. The rate of sweep did not exceed 1.5 x 10⁻³ decade/s, where the frequency range is swept incrementally, the step size was 1 % of preceding frequency value.
- c) The dwell time at each frequency shall be not less than the time necessary for the EUT to be able to respond.
- d) The test was performed with the EUT exposed to both vertically and horizontally polarized fields on each of the four sides.

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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 37 of 54

8.2.3. TEST SETUP



For the actual test configuration, please refer to the related item – Photographs of the Test Configuration. Note:

TABLETOP EQUIPMENT

The EUT installed in a representative system as described in section 7 of EN 61000-4-3 was placed on a non-conductive table 0.8 meters in height. The system under test was connected to the power and signal wire according to relevant installation instructions.

FLOOR STANDING EQUIPMENT

The EUT installed in a representative system as described in section 7 of IEC 61000-4-3 was placed on a non-conductive wood support 0.1 meters in height. The system under test was connected to the power and signal wire according to relevant installation instructions.

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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 38 of 54

8.2.4. TEST RESULT

Product	Wireless Microphone	Environmental Conditions	24.1°C, 51% RH, 101.12 kPa
Model	MO2665	Tested By	Joy Jiang
Test mode	Mode 1	Test Result	Pass

For EN 301 489-1/-17

Frequency (MHz)	Polarity	Position	Field Strength (V/m)	Observation	Performance Criterion
	V&H	Front	3	Note ⊠ 1 □ 2 □ 3	A
90 (CH-	V&H	Rear	3	Note ⊠ 1 □ 2 □ 3	A
80 ~6GHz	V&H	Left	3	Note ⊠ 1 □ 2 □ 3	В
(E)	V&H	Right	3	Note ⊠ 1 □ 2 □ 3	A

For EN 55035

9						
L	Frequency (MHz)	Polarity	Position	Field Strength (V/m)	Observation	Performance Criterion
	80 ~ 1000, 1800, 2600, 3500, 5000	V&H	Front	3,5	Note ⊠ 1 □ 2 □ 3	AG
1	80 ~ 1000, 1800, 2600, 3500, 5000	V&H	Rear	3	Note ⊠ 1 □ 2 □ 3	A
	80 ~ 1000, 1800, 2600, 3500, 5000	V&H	Left	3	Note ⊠ 1 □ 2 □ 3	В
	80 ~ 1000, 1800, 2600, 3500, 5000	V&H	Right	3	Note ⊠ 1 □ 2 □ 3	A

Note:

- 1) No degradation in performance of the EUT was observed.
- 2) During the test, Loss of functionality, after the experiment, the function can automatically return to normal.
- 3) Loss of functionality, but self-recoverable by user, without loss of information or settings.

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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 39 of 54

8.3. ELECTRICAL FAST TRANSIENT (EFT)

8.3.1. TEST SPECIFICATION

Test Standard: EN 301 489-1/-17
Basic Standard: EN 61000-4-4
Test Voltage: Power Line: ±1 kV

Signal/Control Line: ±0.5 kV

Polarity: Positive & Negative

Impulse Frequency:5 kHzImpulse Wave-shape:5/50 nsBurst Duration:15 msBurst Period:300 msTest Duration:2 minsPerformance Criterion:B

8.3.2. TEST PROCEDURE

EUT is placed on a 0.1 m tall wooden table.

EUT operate at normal mode, the transient/burst was 5/50 ns in accordance with BS EN 61000-4-4, both positive and negative polarity burst waveform were applied.

The duration time of each test line was 2 minutes.

8.3.3. TEST SETUP

The EUT installed in a representative system as described in section 7 of EN 61000-4-4.

For the actual test configuration, please refer to the related item – photographs of the test configuration.

8.3.4. TESTRESULT

N/A

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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 40 of 54

8.4. SURGE IMMUNITY TEST

8.4.1. TEST SPECIFICATION

Test Standard: EN 301 489-1/-17 **Basic Standard:** EN 61000-4-5

Combination Wave

Wave-Shape: 1.2/50 μs Open Circuit Voltage

8/20 µs Short Circuit Current

Test Voltage: Power Port \sim Line to line: ± 1 kV, Line to ground: ± 2 kV

Surge Input/Output: Power Line: L-N / L-PE / N-PE

Generator Source Impedance: 2 Ω between networks

12 Ω between network and ground

Polarity: Positive/Negative **Phase Angle:** 0°/90°/180°/270°

Pulse Repetition Rate: 1 time / min

Number of Tests: 5 positive polarity pulses, and 5 negative polarity pulses

Performance Criterion: B

8.4.2. TEST PROCEDURE

EUT is placed on a 0.8 m tall wooden table.

EUT operate at normal mode, two types of combination wave generator (1.2/50 us open-circuit voltage and 8/20 us short-circuit current) are applied to the EUT power supply terminals via the capacitive coupling network.

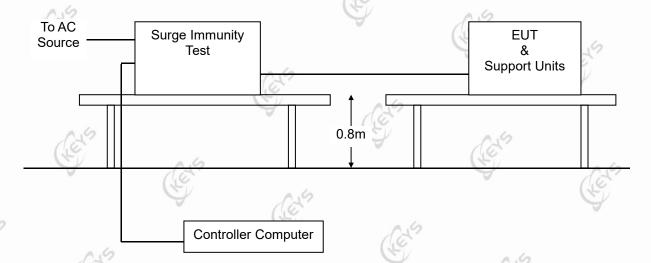
The power cord between the EUT and the coupling/decoupling network shall not exceed 2 m in length.





Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 41 of 54

8.4.3. TEST SETUP



For the actual test configuration, please refer to the related item – Photographs of the Test Configuration.

8.4.4. TEST RESULT

N/A

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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 42 of 54

8.5. CONDUCTED RADIO FREQUENCY DISTURBANCES (CS)

8.5.1. TEST SPECIFICATION

Test Standard: EN 301 489-1/-17 **Basic Standard:** EN IEC 61000-4-6

Frequency Range: 0.15MHz-10MHz: 3V, 10MHz-30MHz: 3V to 1V

30MHz-80MHz: 1V

Field Strength: 3 V

Modulation: 1 kHz Sine Wave, 80 %, AM Modulation

Frequency Step: 1 % of preceding frequency value

Coupled cable: Power Mains, Shielded

Coupling device: CDN-M3/2 (3 wires/2 wires)

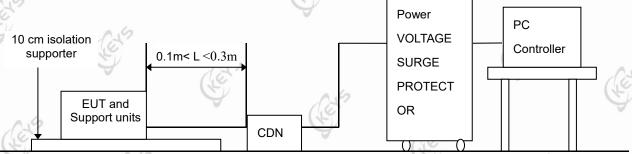
Performance Criterion: A

8.5.2. TEST PROCEDURE

The EUT shall be tested within its intended operating and climatic conditions.

The test shall performed with the test generator connected to each of the coupling and decoupling devices in turn, while the other non-excited RF input ports of the coupling devices are terminated by a 50 Ω load resistor. The frequency range was swept from 150 kHz to 80 MHz, using the signal level established during the setting process and with a disturbance signal of 80 % amplitude. The signal was modulated with a 1 kHz sine wave, pausing to adjust the RF signal level or the switch coupling devices as necessary. The sweep rate was 1.5 x 10^{-3} decades/s. Where the frequency range is swept incrementally, the step size was 1 % of preceding frequency value the dwell time of the amplitude modulated carrier at each frequency was 0.5 s.





 $For the actual \ test \ configuration, please \ refer \ to \ the \ related \ item-Photographs \ of \ the \ Test \ Configuration$

Note: 1) The EUT is setup 0.1 m above Ground Reference Plane

2) All relevant cables shall be provided with the appropriate coupling and decoupling devices at a distance between 0.1 meters and 0.3 meters from the projected geometry of the EUT on the ground reference plane.

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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 43 of 54

8.5.4. TEST RESULT

N/A

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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 44 of 54

8.6. VOLTAGE DIP & VOLTAGE INTERRUPTIONS

8.6.1. TEST SPECIFICATION

Test Standard: EN 301 489-1/-17
Basic Standard: EN IEC 61000-4-11

Test Duration Time: 3 test events in sequence

Interval Between Event: 10 seconds

Phase Angle: 0°

Test Cycle: 3 times

Performance Criterion: voltage dip: $0\% U_T / 0.5 P$, Criterion: B

0 % residual voltage for 0,5 70% U_T / 25 P, Criterion: C

cycle; $0\% U_{\rm T}$ / 250 P, Criterion: C

voltage dip: B

0 % residual voltage for 1 cycle;

voltage dip: B

70 % residual voltage for 25 cycles

(at 50 Hz);B

Voltage interruption:

0 % residual voltage for 250 cycles

(at 50 Hz): C

8.6.2. TEST PROCEDURE

The EUT and support units were located on a wooden table, 0.8 m away from ground floor.

Setting the parameter of tests and then perform the test software of test simulator.

Changes to the voltage level shall occur at 0 degree crossing point in the a.c. voltage waveform.

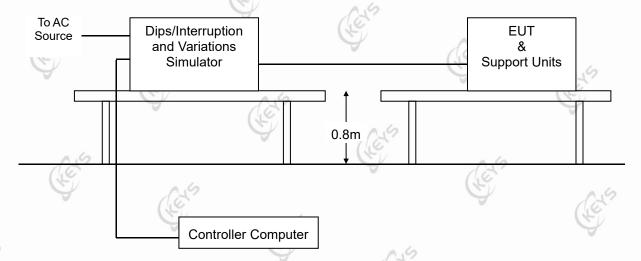
Record the test result in test record form.

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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 45 of 54

8.6.3. TEST SETUP



For the actual test configuration, please refer to the related item – Photographs of the Test Configuration.

8.6.4. TEST RESULT

N/A

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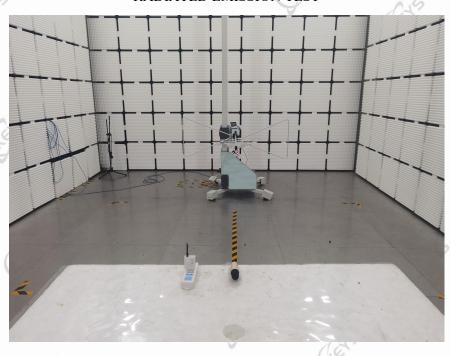


Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 46 of 54

9. PHOTOGRAPHS OF THE TEST CONFIGURATION

CONDUCTED EMISSION TEST

RADIATED EMISSION TEST

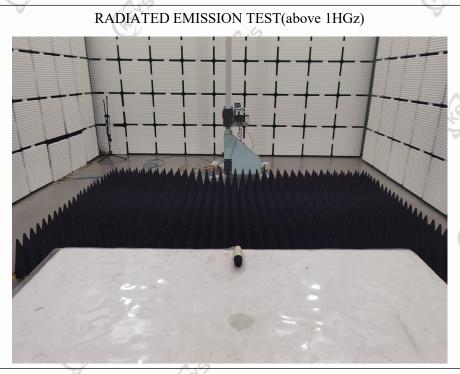


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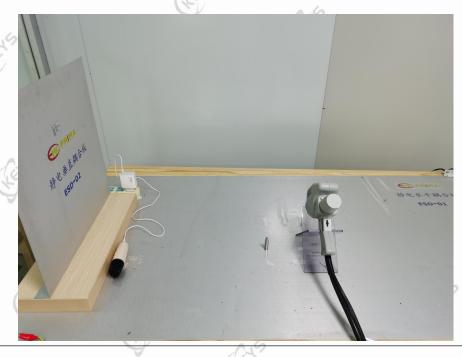
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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 47 of 54



ESD TEST



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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 48 of 54

10. PHOTOGRAPHS OF EUT





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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 49 of 54





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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 50 of 54



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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 51 of 54



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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 52 of 54





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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 53 of 54



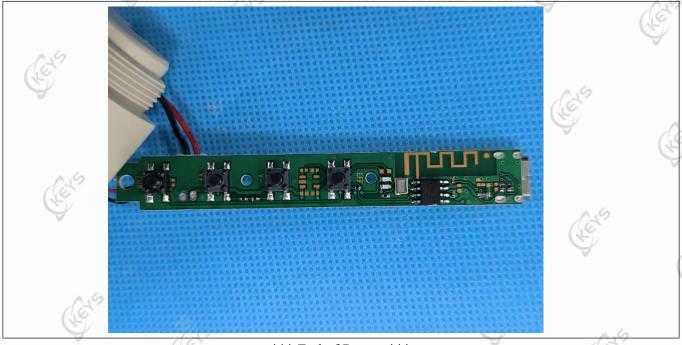


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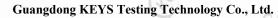
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Report No.: RKEYS250827253 Date: Sep. 02, 2025 Page 54 of 54



*** End of Report ***



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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 1 of 54

CE RED EMC

For

Product:Wireless Speaker Model: MO2665

Report No.: RKEYS250813364

Issued for

Mid Ocean Brands B.V.

Unit 711-716, 7/F., Tower A, 83 King Lam Street, Cheung Sha Wan, Kowloon, Hong Kong

Issued by

Guangdong KEYS Testing Technology Co., Ltd.

Address: Building 1, No.18, Shihuan Road, Dongcheng Subdistrict, Dongguan, Guangdong, China



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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 2 of 54

TABLE OF CONTENTS

	I, TEST CERTIFICATION		
2.	2. TEST SUMMARY		5
3.	3. TEST SITE		6
	3.1. TEST FACILITY		6
	3.2. MEASUREMENT UNCERTAINTY		
	3.3. LIST OF TEST AND MEASUREMENT INSTRUMENTS 错误!	未定义书签	춫。
4.	4. EUT DESCRIPTION	2	.10
5.	S. TEST METHODOLOGY	ν	. 11
	5.1. TEST MODE		. 11
	5.2. EUT SYSTEM OPERATION		. 11
6.	5. SETUP OF EQUIPMENT UNDER TEST		.12
	6.1. DESCRIPTION OF SUPPORT UNITS		. 12
	6.2. CONFIGURATION OF SYSTEM UNDER TEST	A.G.	. 12
7.	7. EMISSION TEST	16	.13
	7.1. CONDUCTED EMISSION MEASUREMENT	<u></u>	. 13
6	7.2. RADIATED EMISSION MEASUREMENT		
	7.3. RADIATED EMISSION MEASUREMENT(ABOVE 1GHz)		
	7.4. HARMONICS CURRENT MEASUREMENT		26
	7.5. VOLTAGE FLUCTUATION AND FLICKS MEASUREMENT		
8.	B. IMMUNITY TEST	969	. 29
	8.1. ELECTROSTATIC DISCHARGE (ESD)	(18	. 32
	8.2. RADIATED, RADIO-FREQUENCY, ELECTROMAGNETIC FIELD (RS)		. 36
Λ	8.3. ELECTRICAL FAST TRANSIENT (EFT)		. 39
16	8.4. SURGE IMMUNITY TEST		.40
Ì	8.5. CONDUCTED RADIO FREQUENCY DISTURBANCES (CS)		. 42
_	8.6. VOLTAGE DIP & VOLTAGE INTERRUPTIONS		.44
	P. PHOTOGRAPHS OF THE TEST CONFIGURATION		
11	10 PHOTOGRAPHS OF FUT	1.0	48

Guangdong KEYS Testing Technology Co., Ltd.



Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 3 of 54

1. TEST CERTIFICATION

Product: Wireless Speaker

Trade mark: N/A

Model: MO2665

Additional

Model(s) N/A

Applicant: Mid Ocean Brands B.V.

Address: Unit 711-716, 7/F., Tower A, 83 King Lam Street, Cheung Sha Wan, Kowloon, Hong

Kong

Manufacturer: 117486

Address: N/A

Sample Received Aug. 13, 2025

Date:

Test Date: Aug.13, 2025 to Aug.18, 2025

Power supply: Type-C Input : DC 5V, 1A

Battery: DC 3.7V, 800mAh

ETSI EN 301 489-1 V2.2.3 (2019-11)

Applicable ETSI EN 301 489-17 V3.2.4 (2020-09)

Standards: EN 55032:2015/A1:2020

EN 55035:2017/A11:2020

Remark: N/A



Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 4 of 54

The above equipment has been tested by Guangdong KEYS Testing Technology Co., Ltd. and found compliance with the requirements in the technical standards mentioned above. The test results presented in this report only relate to the product/system tested. The Other similar equipment will not necessarily produce the same results due to production tolerance and measurement uncertainties.

Prepared by:

Evan Fang

Evan Fang / Engineer

Approved by:

Bruce Zhang / Manager



Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 5 of 54

2. TEST SUMMARY

EMISSION						
Standard	Item Result		Remarks			
EN 55032:2015/A1:2020	Conducted emission (Mains Port)	PASS	Complied with limit			
EN 33032.2013/A1.2020	Radiated emission	PASS	Complied with limit			
EN IEC 61000-3-2:2019+A1:2021	Harmonic current emissions	N/A	Not Applicable			
EN 61000-3-3:2013+A2:2021	Voltage fluctuations & flicker	N/A	Not Applicable			

	IMN	IUNITY	
Standard	Item	Result	Remarks
EN 61000-4-2:2009	ESD	PASS	Complied with the requirements
EN IEC 61000-4-3:2006+A2: 2010	RS	PASS	Complied with the requirements
EN 61000-4-4:2012	EFT	N/A	Not Applicable
EN 61000-4-5:2014 +A1:2017	Surge	N/A	Not Applicable
EN IEC 61000-4-6:2014	6 CS	N/A	Not Applicable
EN IEC 61000-4-11:2004	Voltage dips & voltage variations	N/A	Not Applicable

Note: 1) The test result verdict is decided by the limit of test standard

2)Not Applicable: The EUT is powered by DC.



Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 6 of 54

3. TEST SITE

3.1. TEST FACILITY

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3.2. MEASUREMENT UNCERTAINTY

Parameter	Uncertainty
Conducted Emission(150KHz-30MHz)	±3.2dB
Radiated Emission(30MHz-1GHz)	±4.7dB
Radiated Emission (1GHz-6GHz)	±5.1dB
Radiated Emission (6GHz-18GHz)	±5.1dB

Note 1: This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.

3.3. LIST OF TEST AND MEASUREMENT INSTRUMENTS

3.3.1. For conducted emission at the mains terminals test

Equipment	Manufacturer	Model	Equipment No.	Last Cal.	Cal. Interval
EMI Test Receiver	Rohde&Schwarz	ESCI	KEYS-EL-203	Mar. 03, 2025	1 Year
Pulse Limiter	Rohde&Schwarz	ESH3-Z2	KEYS-EL-201	Mar. 03, 2025	1 Year
LISN	Rohde&Schwarz	ENV216	KEYS-EL-202	Mar. 03, 2025	1 Year
Test software	Tonscend	JS32-RE Version 5.0.0			

3.3.2. For Radiated Emission Measurement(below 1GHz)

Equipment Manufacturer	Model Equipmo	ent Last Cal.	Cal. Interval
------------------------	---------------	---------------	------------------

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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 7 of 54

EMI Test Receiver	Rohde&Schwarz	ESCI7	KEYS-EL-205	Mar. 03, 2025	1 Year
Logarithmic periodic antenna	Schwarzbeck	VULB9168	KEYS-EL-209	Mar. 06, 2025	3 Year
Preamplifier	HP	8447F	KEYS-EL-210	Mar. 03, 2025	1 Year
3m Anechoic Chamber	Taihe MaoRui	9*6*6	KEYS-EL-234	Oct. 12, 2024	5 Year
Test software	Tonscend		JS32-RE Ve	ersion 5.0.0	

3.3.3. ⊠ For radiated emission test (1GHz above)

Name of Equipment	Manufacturer	Model	Equipment No.	Last Cal.	Cal. Interval
EMI Test Receiver	Rohde&Schwarz	ESCI 7	KEYS-EL-205	Mar. 03, 2025	1 Year
Horn antenna	Schwarzbeck	BBHA9120D	KEYS-EL-239	Mar. 06, 2025	3 Year
Preamplifier	(G) /	1-18-53G22	KEYS-EL-240	Mar. 03, 2025	1 Year
Test software	Tonscend	(4)	JS32-RE Ve	ersion 5.0.0	

3.3.3. ⊠ For harmonic current emissions and voltage fluctuations/flicker test

Equipment	Manufacturer	Model	Equipment No.	Last Cal.	Cal. Interval
AC Power Source	California instruments	5001i-400	KEYS-EL-248	May 17, 2025	1 Year
Harmonic and Flicker Analyzer	California instruments	PACS-1	KEYS-EL-249	May 17, 2025	1 Year
Test software	California Instruments	125	CTS 4 Version	on 4.32.0	(To)

3.3.4. ⊠ For electrostatic discharge immunity test

Equipment	Manufacturer	Model	Equipment No	Last Cal.	Cal. Interval
ESD Tester	PRIMA	ESD61002TB	KEYS-EL-215	Mar. 05, 2025	1 Year

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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 8 of 54

3.3.5. For RF Electromagnetic Field Immunity Test

Equipment	Manufacturer	Model	Equipment No.	Last Cal.	Cal. Interval
Amplifier	Micotop	MPA-80-1000- 250	KEYS-EL-258	May 17, 2025	1 Year
Amplifier	Micotop	MPA-1000-60 00-100	KEYS-EL-259	May 19, 2025	1 Year
Power Meter	Agilent	E4417A	KEYS-EL-260	May 17, 2025	1 Year
Power Sensor	Agilent	E9304A	KEYS-EL-261	May 17, 2025	1 Year
Power Sensor	Agilent	E9304A	KEYS-EL-262	May 17, 2025	1 Year
Signal Generator	ROHDE&SCHWA RZ	SMB100A	KEYS-EL-263	May 17, 2025	1 Year
Log-Per-Broadband Antenna	SKET	STLP 9129 PLUS	KEYS-EL-264	May 19, 2025	3 Year

3.3.6. ⊠ For electrical fast transient/burst immunity test

Equipment	Manufacturer	Model	Equipment No.	Last Cal.	Cal. Interval
Fast Transient Burst Simulator	PRIMA	EFT61004TA	KEYS-EL-218	Mar. 03, 2025	1 Year
Clamp	PRIMA	PEFT-C105	KEYS-EL-219	Mar. 03, 2025	1 Year

3.3.7. \boxtimes For surge immunity test

Equipment	Manufacturer	Model	Equipment No.	Last Cal.	Cal. Interval
Lighting Surge Generator	PRIMA	SUG61005TB -2216	KEYS-EL-217	Mar. 03, 2025	1 Year
Coupling/Decoupling	PRIMA	SUG-CDN-10	KEYS-EL-216	Mar. 03, 2025	1 Year

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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 9 of 54

Materials	(6)	o	V	(T)
Network	(4)	0 0.9		(4)

3.3.8. ⊠ For injected currents susceptibility test

				7.1	7
Equipment	Manufacturer	Model	Equipment No.	Last Cal.	Cal. Interval
CS Test system	TESEQ	NSG4070	KEYS-EL-255	May 17, 2025	1 Year
6dB Attenuator	TESEQ	ATN6075	KEYS-EL-256	May 17, 2025	1 Year
CDN	TESEQ	CDN M016	KEYS-EL-254	May 17, 2025	1 Year
EM-Clamp	TESEQ	KEMZ 801A	KEYS-EL-257	May 17, 2025	1 Year

3.3.9. For power frequency magnetic field immunity test

	Equipment	Manufacturer	Model	Equipment No.	Last Cal.	Cal. Interval
2	POWER FREQUENCY MAGNETIC FIELD GENERATION	EVERFINE	EMS61000-8 K	KEYS-EL-273	May 16, 2025	1 Year

3.3.10. \boxtimes For voltage dips and short interruptions immunity test

Equipment	Manufacturer	Model	Equipment No.	Last Cal.	Cal. Interval
Cycle Sag Simulator	PRIMA	DRP61011TB	KEYS-EL-220	Mar. 03, 2025	1 Year

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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 10 of 54

4. EUT DESCRIPTION

Product	Wireless Speaker	(E)		
Model	MO2665	9	(E)	
RF Specification	Bluetooth		9	d
Supplied Voltage	Type-C Input : DC 5V, 1A Battery :DC 3.7V, 800mAh	Cers		0

I/O PORT

I/O PORT TYPES	Q'TY	TESTED WITH
AC Port	1	
DC Port	1	

Models Difference

N/A

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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 11 of 54

5. TEST METHODOLOGY

5.1. TEST MODE

The EUT was tested together with the thereinafter additional components, and a configuration, which produced the worst emission levels, was selected and recorded in this report.

Test Mode 1	EUT + Bluetooth Link	15		77
Test Mode 2	idle	(Te	2 (2	

The following test mode(s) were assessed.

	Test Items	Test Mode
	Conducted Emission	Mode 1
	Radiated Emission	Mode 1
Emission	Radiated Emission above 1HGz	Mode 1
	Harmonic current emissions	N/A
	Voltage fluctuations & flicker	N/A
	ESD	Mode 1
	RS	Mode 1
T	EFT	N/A
Immunity	Surge	N/A
	C/S	N/A
	Dips	N/A

Note:Only the worse mode was record in this report.

5.2. EUT SYSTEM OPERATION

- 1. Set up EUT with the support equipment.
- 2. Make sure the EUT work normally during the test.

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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 12 of 54

6. SETUP OF EQUIPMENT UNDER TEST

6.1. DESCRIPTION OF SUPPORT UNITS

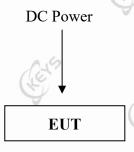
The EUT has been tested as an independent unit together with other necessary accessories or support units. The following support units or accessories were used to form a representative test configuration during the tests.

No.	Equipment	Model	Manufacturer.
1.	Adapter	1	Xiaomi

Note: 1) All the equipment/cables were placed in the worst-case configuration to maximize the emission during the test.

2) Grounding was established in accordance with the manufacturer's requirements and conditions for the intended use.

6.2. CONFIGURATION OF SYSTEM UNDER TEST



(EUT: Wireless Speaker)

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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 13 of 54

7. EMISSION TEST

7.1. CONDUCTED EMISSION MEASUREMENT

7.1.1. LIMIT

EDEOLIENCY	Cla	ss A	Class B		
FREQUENCY (MHz)	Quasi-peak dB(μV)	Average dB(μV)	Quasi-peak dB(μV)	Average dB(μV)	
0.15 - 0.5	79	66	66-56	56-46	
0.5 - 5.0	73	60	56	46	
5.0 - 30.0	73	60	60	50	

Note: 1) The lower limit shall apply at the transition frequencies.

2) The limit decreases in line with the logarithm of the frequency in the range of 0.15 MHz to 0.5 MHz

7.1.2. TEST PROCEDURE

The EUT and Support equipment, if needed, was set up as per the test configuration to simulate typical usage per the user's manual. When the EUT is a tabletop system, a wooden table with a height of 0.8 meters is used and is placed on the ground plane. When the EUT is floor standing equipment, it is placed on the ground plane, which has a 3-12 mm non-conductive covering to insulate the EUT from the ground plane. The EUT should be 0.8 m apart from the AMN, where the mains cable supplied by the manufacturer is longer than 0.8 m, the excess should be folded at the centre into a bundle no longer than 0.4 m, Details please refer to test setup photography.

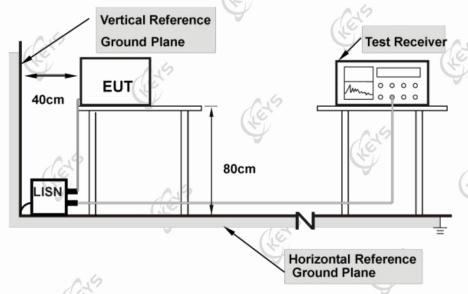
The Receiver scanned from 9 kHz to 30 MHz for emissions in each of the test modes. During the above scans, the emissions were maximized by cable manipulation.

A scanning was taken on the power lines, Line and neutral, recording at least six highest emissions. Emission frequency and amplitude were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit. The test data of the worst-case condition(s) was recorded.



Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 14 of 54

7.1.3. TEST SETUP



Note: 1.Support units were connected to second LISN.

2.Both of LISNs(AMN) are 80 cm from EUT and at least 80 from other units and other metal planes

7.1.4. TEST RESULT

/11/			4.6
Product name	Wireless Speaker	Tested By	Joy Jiang
Model	MO2665	Detector Function	Quasi-peak/AV
Test Mode	Mode 1	6 dB Bandwidth	9 kHz
Environmental Conditions	24.3°C,53% RH, 101.1 kPa	Test Result	Pass

Note:

L = Line Line, N = Neutral Line

Freq. = Emission frequency in MHz

Reading level $(dB\mu V)$ = Receiver reading

Corr. Factor (dB) = attenuator + Cable loss

Level $(dB\mu V)$ = Reading level $(dB\mu V)$ + Corr. Factor (dB)

Limit $(dB\mu V)$ = Limit stated in standard

Over Limit (dB) = Level (dB μ V) – Limit (dB μ V)

QP = Quasi-Peak

AV = Average

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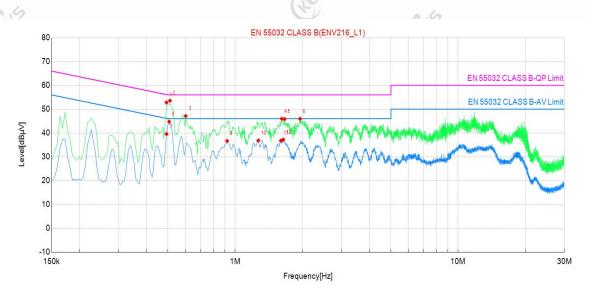
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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 15 of 54

Please refer to the following diagram:

Line:



Suspe	ected Data Lis	t							
NO.	Frequency [MHz]	Reading [dBµV]	Level [dBµV]	Factor [dB]	Limit [dBµV]	Margin [dB]	Phase	Detector	Verdict
1	0.492000	32.82	52.82	20.00	56.13	3.31	L1	QP	PASS
2	0.510000	33.57	53.57	20.00	56.00	2.43	L1	QP	PASS
3	0.600000	27.13	47.13	20.00	56.00	8.87	L1	QP	PASS
4	1.617000	25.98	45.98	20.00	56.00	10.02	L1	QP	PASS
5	1.666500	25.84	45.84	20.00	56.00	10.16	L1	QP	PASS
6	1.954500	25.95	45.95	20.00	56.00	10.05	L1	QP	PASS
7	0.492000	19.60	39.60	20.00	46.13	6.53	L1	AV	PASS
8	0.505500	24.76	44.76	20.00	46.00	1.24	L1	AV	PASS
9	0.919500	16.65	36.65	20.00	46.00	9.35	L1	AV	PASS
10	1.270500	16.83	36.83	20.00	46.00	9.17	L1	AV	PASS
11	1.603500	16.77	36.77	20.00	46.00	9.23	L1	AV	PASS
12	1.644000	17.21	37.21	20.00	46.00	8.79	L1	AV	PASS

Note:(1)Level=Reading+Factor (2)Margin=Limit-Level

1.0

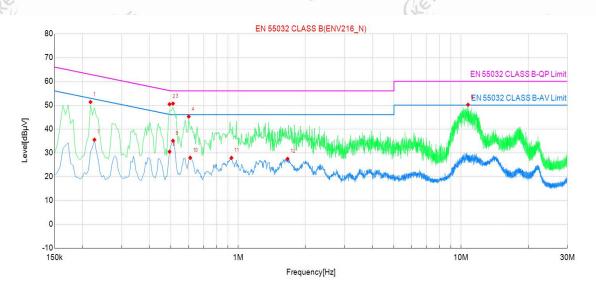
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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 16 of 54

Neutral:



Suspected Data List									
NO.	Frequency [MHz]	Reading [dBµV]	Level [dBµV]	Factor [dB]	Limit [dBµV]	Margin [dB]	Phase	Detector	Verdict
1	0.217500	31.33	51.33	20.00	62.91	11.58	N	QP	PASS
2	0.492000	30.39	50.39	20.00	56.13	5.74	N	QP	PASS
3	0.510000	30.67	50.67	20.00	56.00	5.33	N	QP	PASS
4	0.600000	25.24	45.24	20.00	56.00	10.76	N	QP	PASS
5	10.747500	30.20	50.20	20.00	60.00	9.80	N	QP	PASS
6	10.779000	30.12	50.12	20.00	60.00	9.88	N	QP	PASS
7	0.226500	15.49	35.49	20.00	52.58	17.09	N	AV	PASS
8	0.492000	10.47	30.47	20.00	46.13	15.66	N	AV	PASS
9	0.510000	15.05	35.05	20.00	46.00	10.95	N	AV	PASS
10	0.609000	7.92	27.92	20.00	46.00	18.08	N	AV	PASS
11	0.933000	7.86	27.86	20.00	46.00	18.14	N	AV	PASS
12	1.666500	7.46	27.46	20.00	46.00	18.54	N	AV	PASS

Note:(1)Level=Reading+Factor (2)Margin=Limit-Level

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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 17 of 54

7.2. RADIATED EMISSION MEASUREMENT

7.2.1. LIMITS

	FREQUENCY	Distance	Quasi Peak		
	(MHz)	m	dB(μV/m)		
	30~230	3 25	40		
Г	230~1000	3	47		

Note: 1) The lower limit shall apply at the transition frequencies.

2) Emission level (dB μ V/m) = 20 log Emission level (μ V/m).

7.2.2. TEST PROCEDURE

- a. The EUT was placed on the top of an insulating table 0.8 meters above the ground at a semi-anechoic chamber. The table was rotated 360 degrees to determine the position of the highest radiation.
- b. The EUT was set 3 meters away from the interference-receiving antenna, which was mounted on the top of a variable-height antenna tower.
- c. The antenna is a broadband antenna, and its height is varied from 1 to 4 meter above the ground to determine the maximum value of the field strength. Both horizontal and vertical polarization of the antenna are set to make the measurement.
- d. For each suspected emission, the EUT was arranged to its worst case and then the antenna was tuned to the heights from 1 to 4 meters and the ratable table was turned from 0 degrees to 360 degrees to find the maximum reading.
- e. The test-receiver system was set to Peak Detector Function and Specified Bandwidth with Maximum Hold Mode when the test frequency is below 1GHz.

Note:

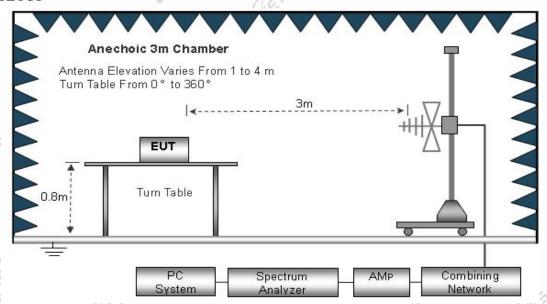
- 1.The resolution bandwidth of test receiver/spectrum analyzer is 120khz for quasi-peak detection(QP) at frequency below 1GHz.
- 2.Emission level(dBμV/m)=Raw Value(dBμV)+Correction Factor(dB/m)
- 3.Correction Factor(dB/m)=Antenna Factor(dB/m)+ Correction Factor(dB)(if the raw value not contains the amplifier);
- 4. Correction Factor(dB/m)=Antenna Factor(dB/m)+ Correction Factor(dB)-Amplifer Gain(dB)(if the raw value contains the amplifier).
 - 5.Margin value=Emission level-Limit value.

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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 18 of 54

7.2.3. TEST SETUP



Note: For the actual test configuration, please refer to the related item – Photographs of the Test Configuration

Test distance define

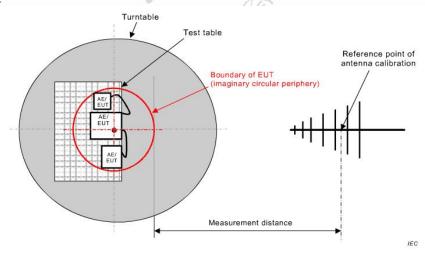


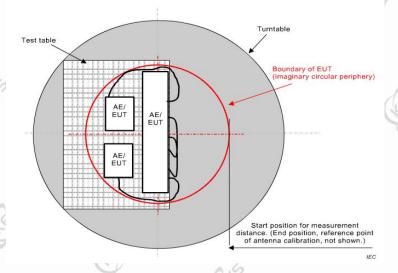
Figure C.1 - Measurement distance

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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 19 of 54



7.2.4. TEST RESULT

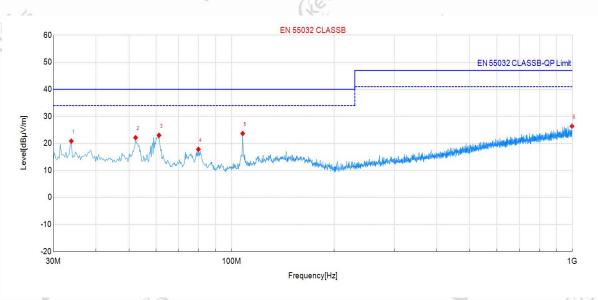
Product name	Wireless Speaker	Tested By	Joy Jiang		
Model	MO2665	Detector Function	Quasi-peak		
Test Mode	Mode 1	RBW	120kHz		
Environmental Conditions	24.3°C, 52% RH, 101.1 kPa	Test Result	Pass		



Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 20 of 54

Please refer to the following diagram:

Vertical:



Susp	ected Data L	ist				-00	31.	VI.			02
NO.	Frequency [MHz]	Reading [dBµV]	Level [dBµV/m]	Factor [dB/m]	Limit [dBµV/m]	Margin [dB]	Height [cm]	Angle [°]	Det	Pol	Verdict
1	33.88	38.40	20.84	-17.56	40.00	19.16	100	251	QP	Vert	PASS
2	52.31	39.54	22.13	-17.41	40.00	17.87	100	1	QP	Vert	PASS
3	61.28	41.24	23.01	-18.23	40.00	16.99	100	109	QP	Vert	PASS
4	79.96	38.49	17.83	-20.66	40.00	22.17	100	193	QP	Vert	PASS
5	107.84	42.75	23.67	-19.08	40.00	16.33	100	335	QP	Vert	PASS
6	997.82	32.81	26.37	-6.44	47.00	20.63	100	119	QP	Vert	PASS

Note:(1)Level=Reading+Factor (2)Margin=Limit-Level

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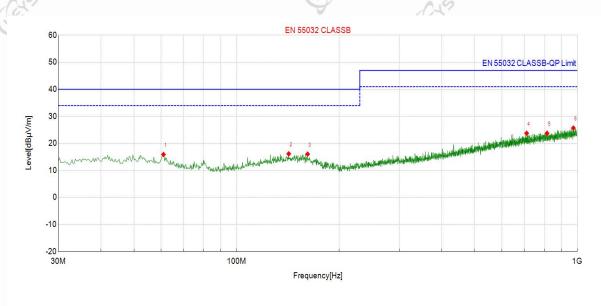
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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 21 of 54

Please refer to the following diagram:

Horizontal::



Susp	ected Data L	ist									
NO.	Frequency [MHz]	Reading [dBµV]	Level [dBµV/m]	Factor [dB/m]	Limit [dBµV/m]	Margin [dB]	Height [cm]	Angle [°]	Det	Pol	Verdict
1	61.04	34.10	15.90	-18.20	40.00	24.10	100	7	QP	Hori	PASS
2	142.28	32.48	16.15	-16.33	40.00	23.85	100	307	QP	Hori	PASS
3	161.68	32.28	16.05	-16.23	40.00	23.95	100	33	QP	Hori	PASS
4	709.97	32.47	23.76	-8.71	47.00	23.24	100	223	QP	Hori	PASS
5	814.73	31.58	23.77	-7.81	47.00	23.23	100	7	QP	Hori	PASS
6	973.33	32.32	25.69	-6.63	47.00	21.31	100	167	QP	Hori	PASS

+

Note:(1)Level=Reading+Factor (2)Margin=Limit-Level

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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 22 of 54

7.3. RADIATED EMISSION MEASUREMENT (ABOVE 1GHz)

7.3.1. LIMITS

FREQUENCY (MHz)	Distance m	Peak dB(μV/m)	Average dB(μV/m)
1000~3000	3	50	54
3000~ 6000	3	70	74

Note: 1) The lower limit shall apply at the transition frequencies.

2) Emission level (dB μ V/m) = 20 log Emission level (μ V/m).

7.3.2. TEST PROCEDURE

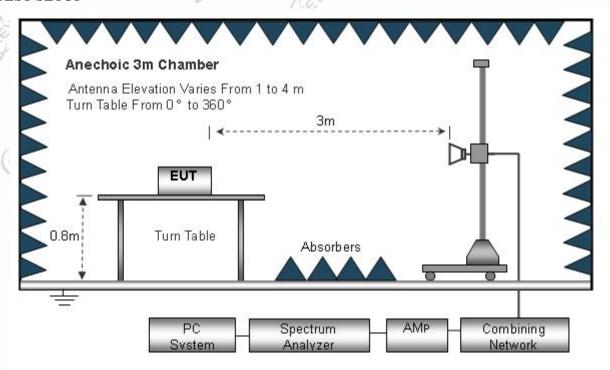
- a. The EUT was placed on the top of an insulating table 0.8 meters above the ground at a semi-anechoic chamber. The table was rotated 360 degrees to determine the position of the highest radiation.
- b. The EUT was set 3 meters away from the interference-receiving antenna, which was mounted on the top of a variable-height antenna tower.
- c. The height of antenna is varied from 1 to 4 meter above the ground ,the height of adjustment depends on the EUT height and the antenna 3dB bandwidth both,to determine the maximum value of the field strength. Both horizontal and vertical polarization of the antenna are set to make the measurement. The boresight should be used during the test above 1GHz.
- d. For each suspected emission, the EUT was arranged to its worst case and then the antenna was tuned to the heights from 1 to 4 meters and the ratable table was turned from 0 degrees to 360 degrees to find the maximum reading.
- e. The test-receiver system was set to Peak Detector Function and Specified Bandwidth with Maximum Hold Mode when the test frequency is above 1 GHz.





Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 23 of 54

7.3.3. TEST SETUP



Note: For the actual test configuration, please refer to the related item - Photographs of the Test Configuration

7.3.4. TEST RESULT

Product name	Wireless Speaker	Tested By	Joy Jiang
Model	MO2665	Detector Function	Peak/AV
Test Mode	Mode 1	RBW	1MHz
Environmental Conditions	24.3°C, 52% RH, 101.1 kPa	Test Result	Pass

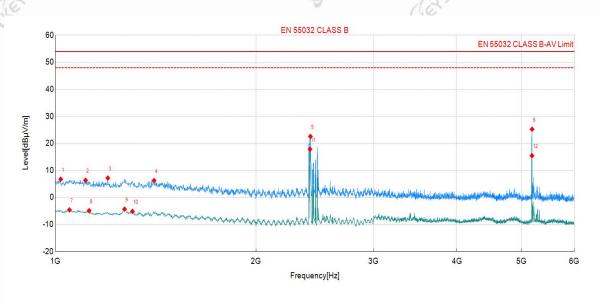
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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 24 of 54

Please refer to the following diagram:

Vertical:



Susp	ected Data L	ist									
NO.	Frequency [MHz]	Reading [dBµV]	Level [dBµV/m]	Factor [dB/m]	Limit [dBµV/m]	Margin [dB]	Height [cm]	Angle [°]	Det	Pol	Verdict
1	1018.75	39.00	6.75	-32.25	74.00	67.25	100	359	QP	Vert	PASS
2	1110.00	39.06	6.35	-32.71	74.00	67.65	100	0	QP	Vert	PASS
3	1198.75	40.33	7.17	-33.16	74.00	66.83	100	4	QP	Vert	PASS
4	1406.25	40.48	6.25	-34.23	74.00	67.75	100	41	QP	Vert	PASS
5	2412.50	59.09	22.58	-36.51	74.00	51.42	100	41	QP	Vert	PASS
6	5185.00	59.64	25.25	-34.39	74.00	48.75	100	2	QP	Vert	PASS
7	1050.00	27.82	-4.59	-32.41	54.00	58.59	100	10	AV	Vert	PASS
8	1123.75	27.89	-4.90	-32.79	54.00	58.90	100	82	AV	Vert	PASS
9	1270.00	29.22	-4.31	-33.53	54.00	58.31	100	10	AV	Vert	PASS
10	1305.00	28.56	-5.15	-33.71	54.00	59.15	100	341	AV	Vert	PASS
11	2408.75	54.37	17.85	-36.52	54.00	36.15	100	359	AV	Vert	PASS
12	5183.75	49.85	15.46	-34.39	54.00	38.54	100	2	AV	Vert	PASS

Note:(1)Level=Reading+Factor (2)Margin=Limit-Level

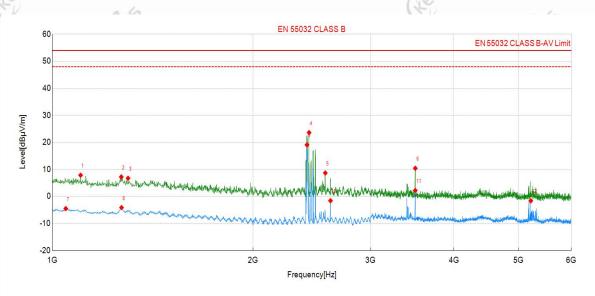
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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 25 of 54

Please refer to the following diagram:

Horizontal::



Susp	ected Data L	ist									
NO.	Frequency [MHz]	Reading [dBµV]	Level [dBµV/m]	Factor [dB/m]	Limit [dBµV/m]	Margin [dB]	Height [cm]	Angle [°]	Det	Pol	Verdict
1	1102.50	40.53	7.86	-32.67	74.00	66.14	100	20	QP	Hori	PASS
2	1268.75	40.76	7.24	-33.52	74.00	66.76	100	1	QP	Hori	PASS
3	1298.75	40.40	6.73	-33.67	74.00	67.27	100	205	QP	Hori	PASS
4	2426.25	60.12	23.63	-36.49	74.00	50.37	100	350	QP	Hori	PASS
5	2566.25	44.93	8.69	-36.24	74.00	65.31	100	60	QP	Hori	PASS
6	3501.25	45.64	10.42	-35.22	74.00	63.58	100	358	QP	Hori	PASS
7	1047.50	27.91	-4.48	-32.39	54.00	58.48	100	9	AV	Hori	PASS
8	1270.00	29.42	-4.11	-33.53	54.00	58.11	100	225	AV	Hori	PASS
9	2408.75	55.62	19.10	-36.52	54.00	34.90	100	1	AV	Hori	PASS
10	2612.50	34.58	-1.58	-36.16	54.00	55.58	100	1	AV	Hori	PASS
11	3501.25	37.44	2.22	-35.22	54.00	51.78	100	358	AV	Hori	PASS
12	5216.25	32.76	-1.61	-34.37	54.00	55.61	100	122	AV	Hori	PASS

Note:(1)Level=Reading+Factor (2)Margin=Limit-Level

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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 26 of 54

7.4. HARMONICS CURRENT MEASUREMENT

7.4.1. LIMITS OF HARMONICS CURRENT MEASUREMENT

Limit fo	r Class A equipment				
Harmoni	Max. permissible				
cs Order	harmonics current				
N	A				
(CC	odd harmonics				
3	2.30				
5	1.14				
7	0.77				
9	0.40				
11	0.33				
13	0.21				
15≦n≦	0.15-(15/-)				
39	0.15x(15/n)				
E	ven harmonics				
2	1.08				
4	0.43				
6	0.30				
8≦n≦4	0.23x8/n				
60	0.2380/11				

	Limit for Class D equ	ipment (
Harmonics Order	Max. permissible harmonics current per watt mA/W	Max. permissible harmonics current
	Odd Harmonics of	nly
3	3.4	2.30
5.6	1.9	1.14
(9	1.0	0.77
9	0.5	0.40
11	0.35	0.33
13	0.30	0.21
15 ≦ n ≦ 39 (odd harmonics only)	3.85/n	0.15x(15/n)
	(F)	(E)
0.49		A Constant
(te	0.6	V

			1.10		
(E)	Li	imit for Class C equip	ment	025	
Harmonics Order	Ma	x. permissible harmon	ics current	expressed as a pe	rcentage of the
n	(FC)	input current	at the fundar	mental frequency	A ((C)
2	A	(E)	2		9
3		9	30xF	7	
5,6			10	0.60	
(18)	. (0		7	(E	
9	(6		5	9	(E)
11≤n<≤39		05			(6)
(odd harmonics only)		(1º)	3		
F is the circuit power factor		4	(Tex		

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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 27 of 54

Note: Class A, B, C and D are classified according to item 7.4.2.of this report

7.4.2. TEST PROCEDURE

The EUT was placed on the top of a wooden table 0.8 meters above the ground and operated to produce the maximum harmonic. The classification of EUT is according to section 5 of EN 61000-3-2.

The EUT is classified as follows:

Class A:

Balanced three-phase equipment, Household appliances excluding equipment as Class D, Tools excluding portable tools, Dimmers for incandescent lamps, audio equipment, equipment not specified in one of the three other classes.

Class B:

Portable tools; Arc welding equipment which is not professional equipment.

Class C:

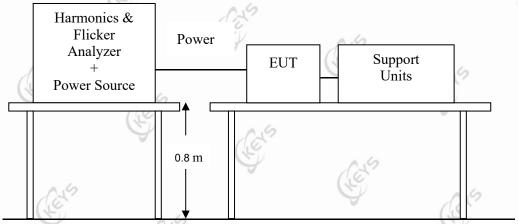
Lighting equipment

Class D:

Equipment having a specified power less than or equal to 600 W of the following types: Personal computers and personal computer monitors and television receivers.

The correspondent test program of test instrument to measure the current harmonics emanated from EUT is chosen. The measure time shall be not less than the time necessary for the EUT to be exercised.

7.4.3. TEST SETUP



For the actual test configuration, please refer to the related item – Photographs of the Test Configuration.

7.4.4. TEST RESULT

N/A

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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 28 of 54

7.5. VOLTAGE FLUCTUATION AND FLICKS MEASUREMENT

7.5.1. LIMITS OF VOLTAGE FLUCTUATION AND FLICKS MEASUREMENT

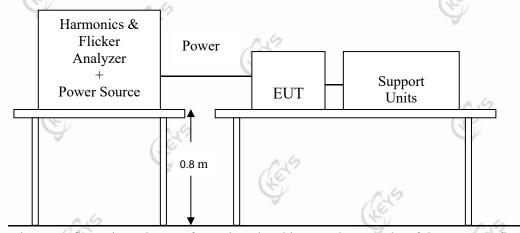
TEST ITEM	LIMIT	REMARK
P_{st}	1.0	P _{st} means short-term flicker indicator.
P _{lt}	0.65	P _{lt} means long-term flicker indicator.
T _{dt} (ms)	500	T _{dt} means maximum time that dt exceeds 3 %.
d _{max} (%)	4/6/7 %	d _{max} means maximum relative voltage change.
dc (%)	3.3 %	dc means relative steady-state voltage change

7.5.2. TEST PROCEDURE

The EUT was placed on the top of a wooden table 0.8 meters above the ground and operated to produce the most unfavorable sequence of voltage changes under lighting operating conditions.

During the flick measurement, the measure time shall include that part of whole operation cycle in which the EUT produce the most unfavorable sequence of voltage changes. The observation period for short-term flicker indicator is 10 minutes and the observation period for long-term flicker indicator is 2 hours.

7.5.3. TEST SETUP



For the actual test configuration, please refer to the related item – Photographs of the Test Configuration.

7.5.4. TEST RESULT

N/A

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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 29 of 54

8. IMMUNITY TEST

PERFORMANCE CRITERIA DESCRIPTION

EN 301 489-1 V2.2.3 Clause 6 requirements:

Performance criteria for continuous phenomena

During the test, the equipment shall:

- continue to operate as intended;
- not unintentionally transmit;
- not unintentionally change its operating state;
- not unintentionally change critical stored data

Performance criteria for transient phenomena

For all ports and transient phenomena with the exception described below, the following applies:

- The application of the transient phenomena shall not result in a change of the mode of operation (e.g. unintended transmission) or the loss of critical stored data.
- After application of the transient phenomena, the equipment shall operate as intended.

For surges applied to symmetrically operated wired network ports intended to be connected directly to outdoor lines the following criteria applies:

- For products with only one symmetrical port intended for connection to outdoor lines, loss of function is allowed, provided the function is self-recoverable, or can be otherwise restored. Information stored in non-volatile memory, or protected by a battery backup, shall not be lost.
- For products with more than one symmetrical port intended for connection to outdoor lines, loss of function on the port under test is allowed, provided the function is self-recoverable. Information stored in non-volatile memory, or protected by a battery backup, shall not be lost.

EN 301 489-17 V3.2.4 Clause 6 requirements:

- 6 General performance criteria
- 6.1The performance criteria are:
- performance criteria A for immunity tests with phenomena of a continuous nature;
- performance criteria B for immunity tests with phenomena of a transient nature;
- performance criteria C for immunity tests with power interruptions exceeding a certain time.

The equipment shall meet the minimum performance criteria as specified in the following clauses.

- 6.2 Performance table
- 6.2.1 Performance criteria overview

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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 30 of 54

Criteria	During test	After test
1.6		(i.e. as a result of the application of the test)
A	Shall operate as intended.	Shall operate as intended.
	(See note).	Shall be no degradation of performance.
	Shall be no loss of function.	Shall be no loss of function.
	Shall be no unintentional transmissions.	Shall be no loss of critical stored data.
В	May be loss of function.	Functions shall be self-recoverable.
(4)	15	Shall operate as intended after recovering.
	(E)	Shall be no loss of critical stored data.
С	May be loss of function.	Functions shall be recoverable by the operator.
	9	Shall operate as intended after recovering.
16	6	Shall be no loss of critical stored data
NOTE: Operat	e as intended during the test allows a level of	of degradation in accordance with clause 6.2.2.

6.2.2 Minimum performance level

For equipment that supports a PER or FER, the minimum performance level shall be a PER or FER less than or equal to 10 %.

For equipment that does not support a PER or a FER, the minimum performance level shall be no loss of the wireless transmission function needed for the intended use of the equipment.

6.3 Performance criteria for Continuous phenomena

The performance criteria A shall apply.

Where the EUT is a transmitter in standby mode, unintentional transmission shall not occur during the test.

Where the EUT is a transceiver in receive mode, unintentional transmission shall not occur during the test.

6.4 Performance criteria for Transient phenomena

The performance criteria B shall apply, except for voltage dips greater than or equal to 100 ms and voltage interruptions of 5 000 ms duration, for which performance criteria C shall apply.

Where the EUT is a transmitter in standby mode, unintentional transmission shall not occur as a result of the application of the test.

Where the EUT is a transceiver in receive mode, unintentional transmission shall not occur as a result of the application of the test.

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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 31 of 54

	A.6
Criteria A:	During and after the test the EUT shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed below a minimum performance level specified by the manufacturer when the EUT is used as intended. The performance level may be replaced by a permissible loss of performance. If the minimum performance level or the permissible performance loss is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the EUT if used as intended.
Criteria B:	After the test, the EUT shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed, after the application of the phenomena below a performance level specified by the manufacturer, when the EUT is used as intended. The performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is allowed. However, no change of operating state or stored data is allowed to persist after the test. If the minimum performance level (or the permissible performance loss) is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the EUT if used as intended.
Criteria C:	During and after testing, a temporary loss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls or cycling of the power to the EUT by the user in accordance with the manufacturer's instructions. Functions, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be lost.



Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 32 of 54

8.1. ELECTROSTATIC DISCHARGE (ESD)

8.1.1. TEST SPECIFICATION

Test Standard: EN 301 489-1/-17 EN55035

Basic Standard: EN 61000-4-2

Discharge Impedance: 330Ω **Charging Capacity:** 150 pF

Discharge Voltage: Air Discharge: ±8 kV (Direct)

Contact Discharge: ± 4 kV (Direct/Indirect)

Polarity: Positive & Negative

Number of Discharge:

10 (Air discharge for single polarity discharge)
10 (Contact discharge for single polarity discharge)

Discharge Mode: 1 time/s

Performance Criterion: B

8.1.2. TEST PROCEDURE

The discharges shall be applied in two ways:

- a) Contact discharges to the conductive surfaces and coupling planes:
 - 20 dischargers (10 with positive and10 with negative polarity) shall be applied on each accessible metallic part of the enclosure, terminals are excluded. In case of a non-conductive enclosure, dischargers shall be applied on the horizontal or vertical coupling planes. Test shall be performed at a maximum repetition rate of one discharge per second.
- b) Air discharges at slots and apertures and insulating surfaces:
 - On those parts of the EUT where it is not possible to perform contact discharge testing, the equipment should be investigated to identify user accessible points where breakdown may occur. Such points are tested using the air discharge method. This investigation should be restricted to those area normally handled by the user. A minimum of 10 single air discharges shall be applied to the selected test point for each such area.

The basic test procedure was in accordance with EN 61000-4-2:

- a) The EUT was located 0.1 m minimum from all side of the HCP (dimensions 1.6 m x 0.8 m).
- b) The support units were located another table 30 cm away from the EUT, but direct support unit was/were located at same location as EUT on the HCP and keep at a distance of 10cm with EUT.
- c) The time interval between two successive single discharges was at least 1 second.
- d) Contact discharges were applied to the non-insulating coating, with the pointed tip of the generator penetrating the coating and contacting the conducting substrate.

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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 33 of 54

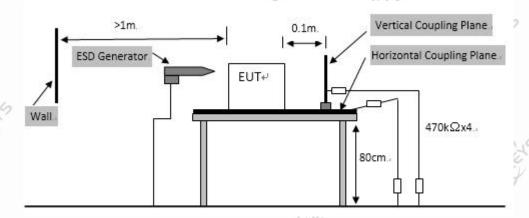
- e) Air discharges were applied with the round discharge tip of the discharge electrode approaching the EUT as fast as possible (without causing mechanical damage) to touch the EUT. After each discharge, the ESD generator was removed from the EUT and re-triggered for a new single discharge. The test was repeated until all discharges were complete.
- f) At least ten single discharges (in the most sensitive polarity) were applied at the front edge of each HCP opposite the center point of each unit of the EUT and 0.1 meter from the front of the EUT. The long axis of the discharge electrode was in the plane of the HCP and perpendicular to its front edge during the discharge.
- g) At least ten single discharges (in the most sensitive polarity) were applied to the center of one vertical edge of the Vertical Coupling Plane (VCP) in sufficiently different positions that the four faces of the EUT were completely illuminated. The VCP (dimensions 0.5 m x 0.5 m) was placed vertically to and 0.1 meter from the EUT

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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 34 of 54

8.1.3. TEST SETUP



For the actual test configuration, please refer to the related item – Photographs of the Test Configuration.

Note:

1) TABLE-TOP EQUIPMENT

The configuration consisted of a wooden table 0.8 meters high standing on the ground reference plane (GRP). The GRP consisted of a sheet of aluminum at least 0.25 mm thick, and 2.5 meters square connected to the protective grounding system. A horizontal coupling plane (HCP) $(1.6 \text{ m} \times 0.8 \text{ m})$ was placed on the table and attached to the GRP by means of a cable with 940k total impedance. The equipment under test, was installed in a representative system as described in section 7 of EN 61000-4-2, and its cables were placed on the HCP and isolated by an insulating support of 0.5 mm thickness. A distance of 1-meter minimum was provided between the EUT and the walls of the laboratory and any other metallic structure.

2) FLOOR-STANDING EQUIPMENT

The equipment under test was installed in a representative system as described in section 7 of IEC 61000-4-2, and its cables were isolated from the ground reference plane by an insulating support of 0.1 meter thickness. The GRP consisted of a sheet of aluminum that is at least 0.25 mm thick, and 2.5 meters square connected to the protective grounding system and extended at least 0.5 meters from the EUT on all sides.

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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 35 of 54

8.1.4. TEST RESULT

Product	Wireless Speaker	Environmental Conditions	24.1°C, 55% RH, 101.14 kPa
Model	MO2665	Tested By	Joy Jiang
Test mode	Mode 1	Test Result	Pass

Discharge Type	Level (kV)	Test Point	Observation	Performance Criterion
Contact Discharge	±4	1	Note \square 1 \boxtimes 2 \square 3	В
Direct Air Discharge	± 8	2	Note \square 1 \boxtimes 2 \square 3	В
Indirect Discharge (HCP)	± 4	3	Note $\square 1 \boxtimes 2 \square 3$	В
Indirect Discharge (VCP)	±4	3	Note □ 1 ⊠ 2 □ 3	A

Test point:

- 1. All insulated enclosure and seams.
- 2.All accessible metal parts of the enclosure
- 3.All side

Note:

- 1) No degradation in performance of the EUT was observed.
- 2) During the test, Loss of functionality, after the experiment, the function can automatically return to normal.
- 3) Loss of functionality, but self-recoverable by user, without loss of information or settings.

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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 36 of 54

8.2. RADIATED, RADIO-FREQUENCY, ELECTROMAGNETIC FIELD (RS)

8.2.1. TEST SPECIFICATION

Test Standard: EN 301 489-1/-17 EN55035

Basic Standard: EN IEC 61000-4-3

Frequency Range: 80 ~6GHz 80 MHz ~ 1000 MHz, 1800MHz,

2600MHz, 3500MHz, 5000MHz

Field Strength: 3 V/m

Modulation: 1 kHz Sine Wave, 80 %, AM Modulation

Frequency Step: 1 % of preceding frequency value

Polarity of Antenna: Horizontal and Vertical

Test Distance: 3 m
Antenna Height: 1.5 m
Performance Criterion: A

8.2.2. TEST PROCEDURE

The test procedure was in accordance with EN IEC 61000-4-3

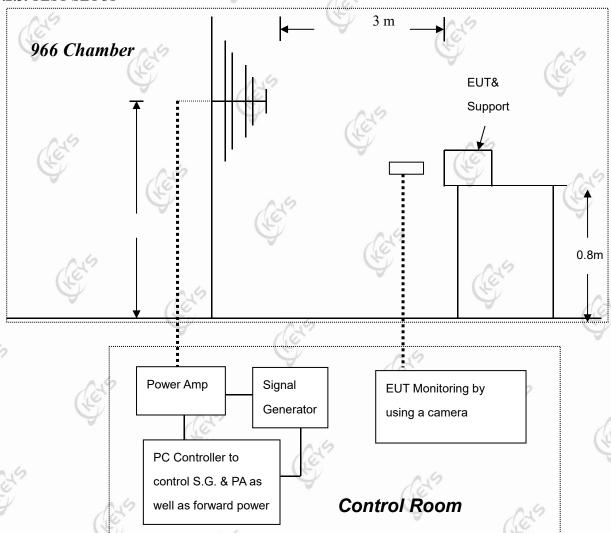
- a) The testing was performed in a fully anechoic chamber. The transmit antenna was located at a distance of 3 meters from the EUT.
- b) The frequency range is swept from 80 MHz to 1000 MHz, with the signal 80% amplitude modulated with a 1 kHz sine-wave. The rate of sweep did not exceed 1.5 x 10⁻³ decade/s, where the frequency range is swept incrementally, the step size was 1 % of preceding frequency value.
- c) The dwell time at each frequency shall be not less than the time necessary for the EUT to be able to respond.
- d) The test was performed with the EUT exposed to both vertically and horizontally polarized fields on each of the four sides.

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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 37 of 54

8.2.3. TEST SETUP



For the actual test configuration, please refer to the related item – Photographs of the Test Configuration. Note:

TABLETOP EQUIPMENT

The EUT installed in a representative system as described in section 7 of EN 61000-4-3 was placed on a non-conductive table 0.8 meters in height. The system under test was connected to the power and signal wire according to relevant installation instructions.

FLOOR STANDING EQUIPMENT

The EUT installed in a representative system as described in section 7 of IEC 61000-4-3 was placed on a non-conductive wood support 0.1 meters in height. The system under test was connected to the power and signal wire according to relevant installation instructions.

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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 38 of 54

8.2.4. TEST RESULT

Product	Wireless Speaker	Environmental Conditions	24.1°C, 51% RH, 101.12 kPa
Model	MO2665	Tested By	Joy Jiang
Test mode	Mode 1	Test Result	Pass

For EN 301 489-1/-17

Frequency (MHz)	Polarity	Position	Field Strength (V/m)	Observation	Performance Criterion
	V&H	Front	3	Note $\boxtimes 1 \square 2 \square 3$	A
90 (CH-	V&H	Rear	3	Note ⊠ 1 □ 2 □ 3	A
80 ~6GHz	V&H	Left	3	Note ⊠ 1 □ 2 □ 3	В
(P)	V&H	6 Right	3	Note ⊠ 1 □ 2 □ 3	A

For EN 55035

9						
L	Frequency (MHz)	Polarity	Position	Field Strength (V/m)	Observation	Performance Criterion
	80 ~ 1000, 1800, 2600, 3500, 5000	V&H	Front	3,5	Note ⊠ 1 □ 2 □ 3	AG
1	80 ~ 1000, 1800, 2600, 3500, 5000	V&H	Rear	3	Note ⊠ 1 □ 2 □ 3	A
	80 ~ 1000, 1800, 2600, 3500, 5000	V&H	Left	3	Note ⊠ 1 □ 2 □ 3	A G
	80 ~ 1000, 1800, 2600, 3500, 5000	V&H	Right	3	Note ⊠ 1 □ 2 □ 3	A

Note:

- 1) No degradation in performance of the EUT was observed.
- 2) During the test, Loss of functionality, after the experiment, the function can automatically return to normal.
- 3) Loss of functionality, but self-recoverable by user, without loss of information or settings.

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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 39 of 54

8.3. ELECTRICAL FAST TRANSIENT (EFT)

8.3.1. TEST SPECIFICATION

Test Standard: EN 301 489-1/-17 EN55035

Basic Standard: EN 61000-4-4

Test Voltage: Power Line: ±1 kV

Signal/Control Line: ±0.5 kV

Polarity: Positive & Negative

Impulse Frequency:5 kHzImpulse Wave-shape:5/50 nsBurst Duration:15 msBurst Period:300 msTest Duration:2 mins

Performance Criterion: B

8.3.2. TEST PROCEDURE

EUT is placed on a 0.1 m tall wooden table.

EUT operate at normal mode, the transient/burst was 5/50 ns in accordance with BS EN 61000-4-4, both positive and negative polarity burst waveform were applied.

The duration time of each test line was 2 minutes.

8.3.3. TEST SETUP

The EUT installed in a representative system as described in section 7 of EN 61000-4-4.

For the actual test configuration, please refer to the related item – photographs of the test configuration.

8.3.4. TESTRESULT

N/A

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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 40 of 54

8.4. SURGE IMMUNITY TEST

8.4.1. TEST SPECIFICATION

Test Standard: EN 301 489-1/-17 EN 55035

Basic Standard: EN 61000-4-5

Combination Wave

Wave-Shape: 1.2/50 μs Open Circuit Voltage

8/20 µs Short Circuit Current

Test Voltage: Power Port \sim Line to line: ± 1 kV, Line to ground: ± 2 kV

Surge Input/Output: Power Line: L-N / L-PE / N-PE

Generator Source Impedance: 2 Ω between networks

12 Ω between network and ground

Polarity: Positive/Negative

Phase Angle: 0°/90°/180°/270°

Pulse Repetition Rate: 1 time / min

Number of Tests: 5 positive polarity pulses, and 5 negative polarity pulses

Performance Criterion: B

8.4.2. TEST PROCEDURE

EUT is placed on a 0.8 m tall wooden table.

EUT operate at normal mode, two types of combination wave generator (1.2/50 us open-circuit voltage and 8/20 us short-circuit current) are applied to the EUT power supply terminals via the capacitive coupling network.

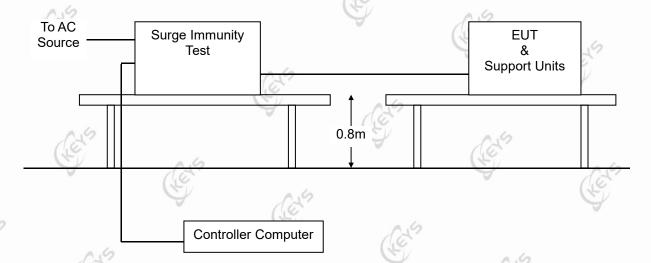
The power cord between the EUT and the coupling/decoupling network shall not exceed 2 m in length.





Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 41 of 54

8.4.3. TEST SETUP



For the actual test configuration, please refer to the related item – Photographs of the Test Configuration.

8.4.4. TEST RESULT

N/A

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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 42 of 54

8.5. CONDUCTED RADIO FREQUENCY DISTURBANCES (CS)

8.5.1. TEST SPECIFICATION

Test Standard: EN 301 489-1/-17 EN 55035

Basic Standard: EN IEC 61000-4-6

Frequency Range: 0.15MHz-10MHz: 3V, 10MHz-30MHz: 3V to 1V

30MHz-80MHz: 1V

Field Strength: 3 V

Modulation: 1 kHz Sine Wave, 80 %, AM Modulation

Frequency Step: 1 % of preceding frequency value

Coupled cable: Power Mains, Shielded

Coupling device: CDN-M3/2 (3 wires/2 wires)

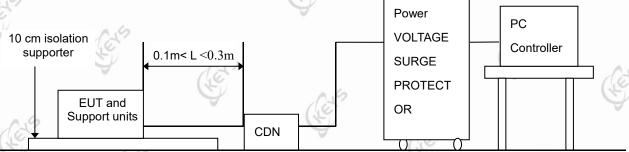
Performance Criterion: A

8.5.2. TEST PROCEDURE

The EUT shall be tested within its intended operating and climatic conditions.

The test shall performed with the test generator connected to each of the coupling and decoupling devices in turn, while the other non-excited RF input ports of the coupling devices are terminated by a 50 Ω load resistor. The frequency range was swept from 150 kHz to 80 MHz, using the signal level established during the setting process and with a disturbance signal of 80 % amplitude. The signal was modulated with a 1 kHz sine wave, pausing to adjust the RF signal level or the switch coupling devices as necessary. The sweep rate was 1.5 x 10^{-3} decades/s. Where the frequency range is swept incrementally, the step size was 1 % of preceding frequency value the dwell time of the amplitude modulated carrier at each frequency was 0.5 s.





 $For the actual \ test \ configuration, please \ refer \ to \ the \ related \ item-Photographs \ of \ the \ Test \ Configuration$

Note: 1) The EUT is setup 0.1 m above Ground Reference Plane

2) All relevant cables shall be provided with the appropriate coupling and decoupling devices at a distance between 0.1 meters and 0.3 meters from the projected geometry of the EUT on the ground reference plane.

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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 43 of 54

8.5.4. TEST RESULT

N/A

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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 44 of 54

8.6. VOLTAGE DIP & VOLTAGE INTERRUPTIONS

8.6.1. TEST SPECIFICATION

Test Standard: EN 301 489-1/-17 EN 55035

Basic Standard: EN IEC 61000-4-11

Test Duration Time: 3 test events in sequence

Interval Between Event: 10 seconds

Phase Angle: 0°

Test Cycle: 3 times

Performance Criterion: voltage dip: $0\% U_T / 0.5 P$, Criterion: B

0 % residual voltage for 0,5 70% U_T / 25 P, Criterion: C

cycle; $0\% U_{\rm T}$ / 250 P, Criterion: C

voltage dip: B

0 % residual voltage for 1 cycle;

voltage dip: B

70 % residual voltage for 25 cycles

(at 50 Hz);B

Voltage interruption:

0 % residual voltage for 250 cycles

(at 50 Hz): C

8.6.2. TEST PROCEDURE

The EUT and support units were located on a wooden table, 0.8 m away from ground floor.

Setting the parameter of tests and then perform the test software of test simulator.

Changes to the voltage level shall occur at 0 degree crossing point in the a.c. voltage waveform.

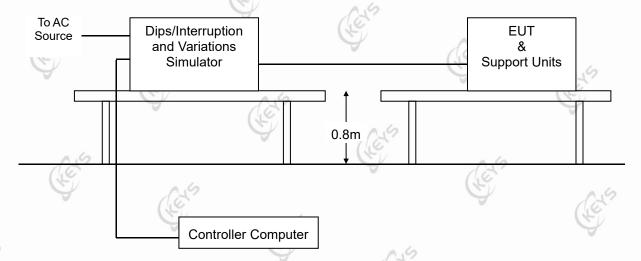
Record the test result in test record form.

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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 45 of 54

8.6.3. TEST SETUP



For the actual test configuration, please refer to the related item – Photographs of the Test Configuration.

8.6.4. TEST RESULT

N/A

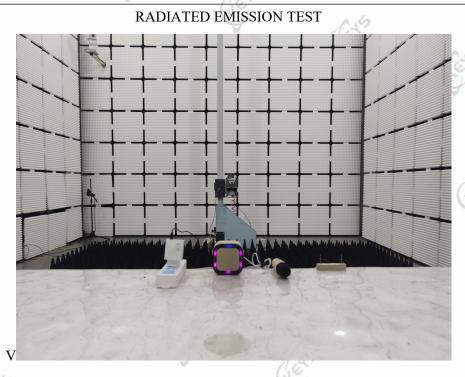
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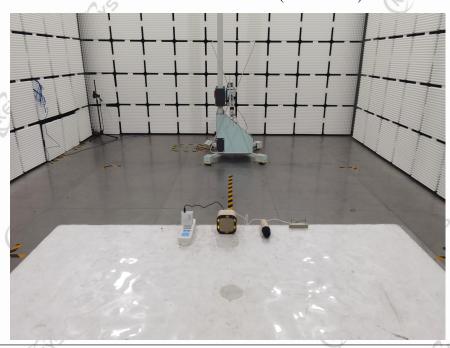


Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 46 of 54

9. PHOTOGRAPHS OF THE TEST CONFIGURATION



RADIATED EMISSION TEST(above 1HGz)



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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 47 of 54





CONDUCTION TEST



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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 48 of 54

10. PHOTOGRAPHS OF EUT





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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 49 of 54





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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 50 of 54





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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 51 of 54





Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 52 of 54





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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 53 of 54



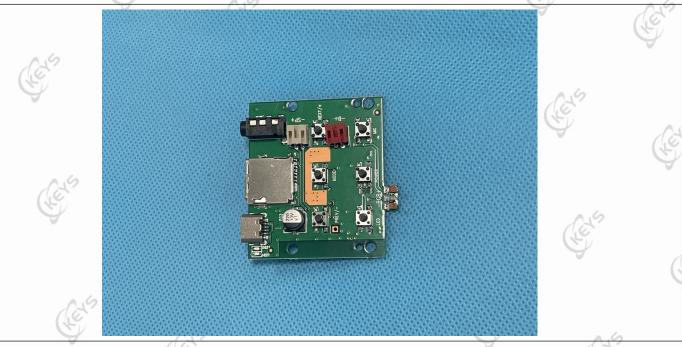


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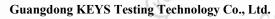
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Report No.: RKEYS250813364 Date: Sep. 02, 2025 Page 54 of 54



*** End of Report ***



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